

*Innovation for Our Energy Future*

# **Semiconductor Materials and Tandem Cells for Photoelectrochemical Hydrogen Production: $GaP_{1-x}N_x$ and $Cu(In,Ga)Se,S$**

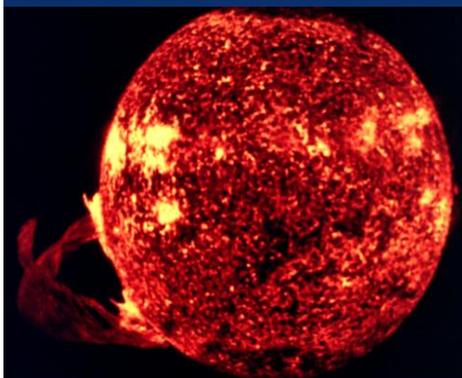
ICMR Symposium on Materials Issues in Hydrogen Production  
and Storage

Santa Barbara, CA

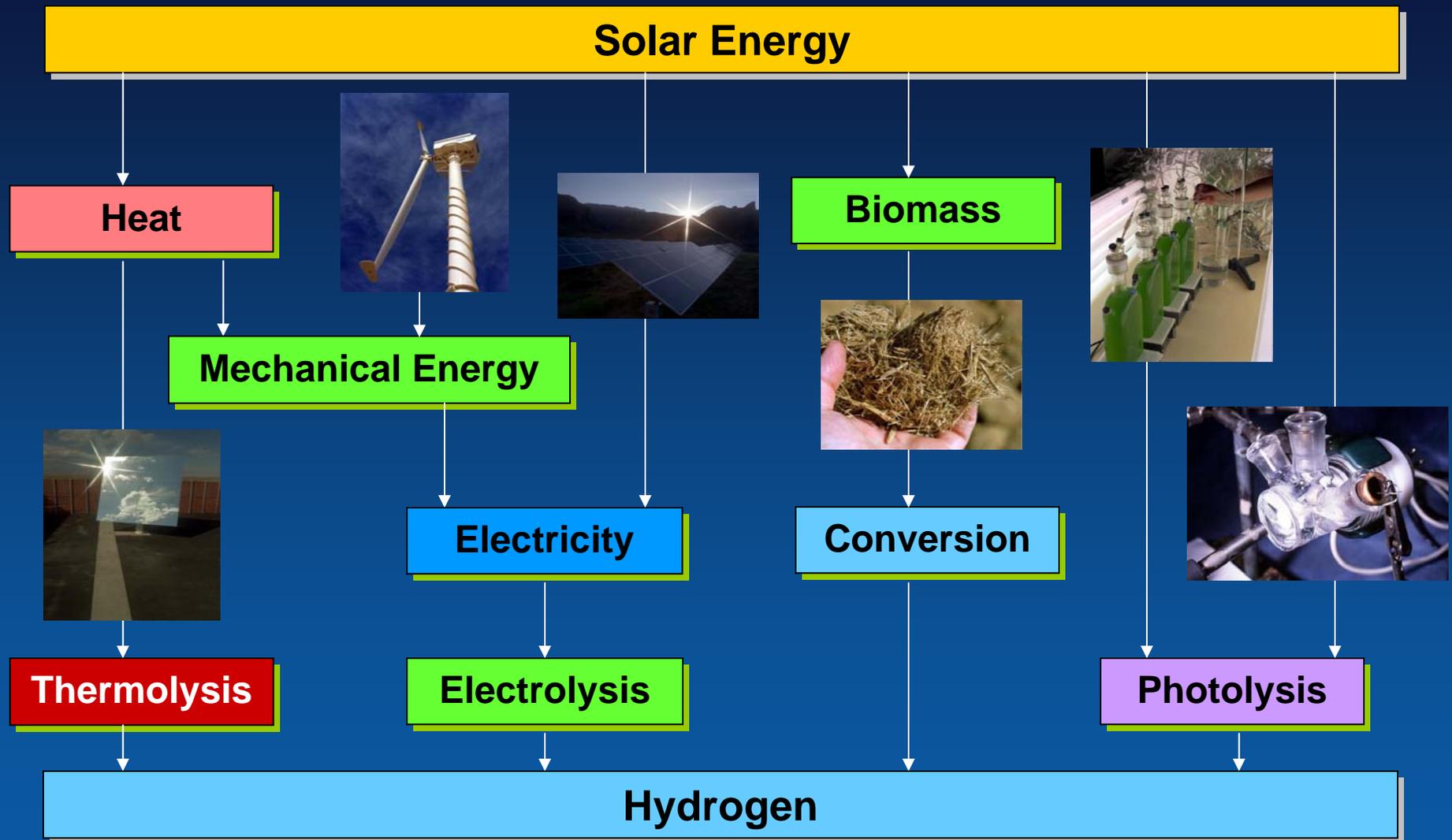
*August 24, 2006*

John A. Turner

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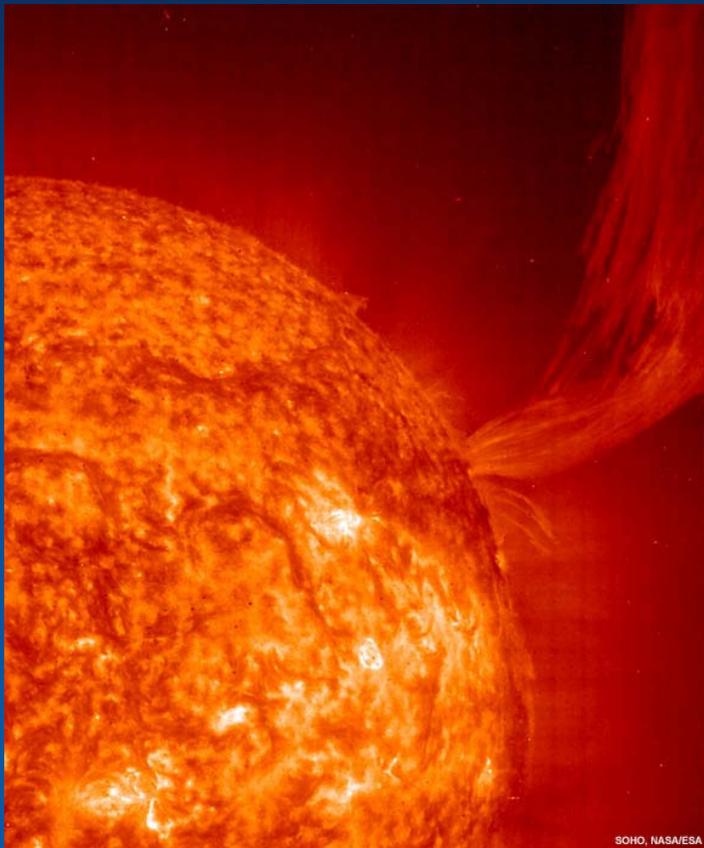
# Sustainable Paths to Hydrogen



# Direct Conversion Systems

Visible light has sufficient energy to split water ( $\text{H}_2\text{O}$ ) into **Hydrogen and Oxygen**

Combination of a Light Harvesting System and a Water Splitting System

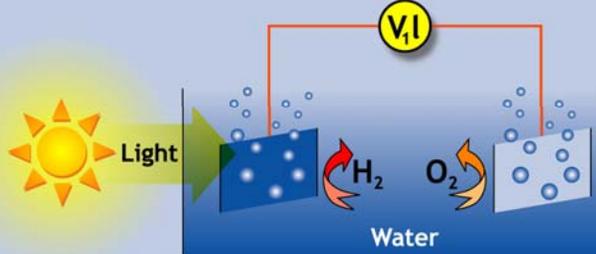
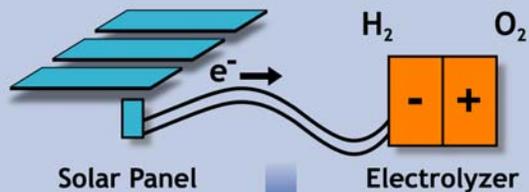


- ✓ Semiconductor photoelectrolysis
- ✓ Photobiological Systems
- ✓ Homogeneous water splitting
- ✓ Heterogeneous water splitting
- ✓ Thermal cycles

(Sunlight and Water to Hydrogen with No External Electron Flow)

# Photoelectrochemical-Based Direct Conversion Systems

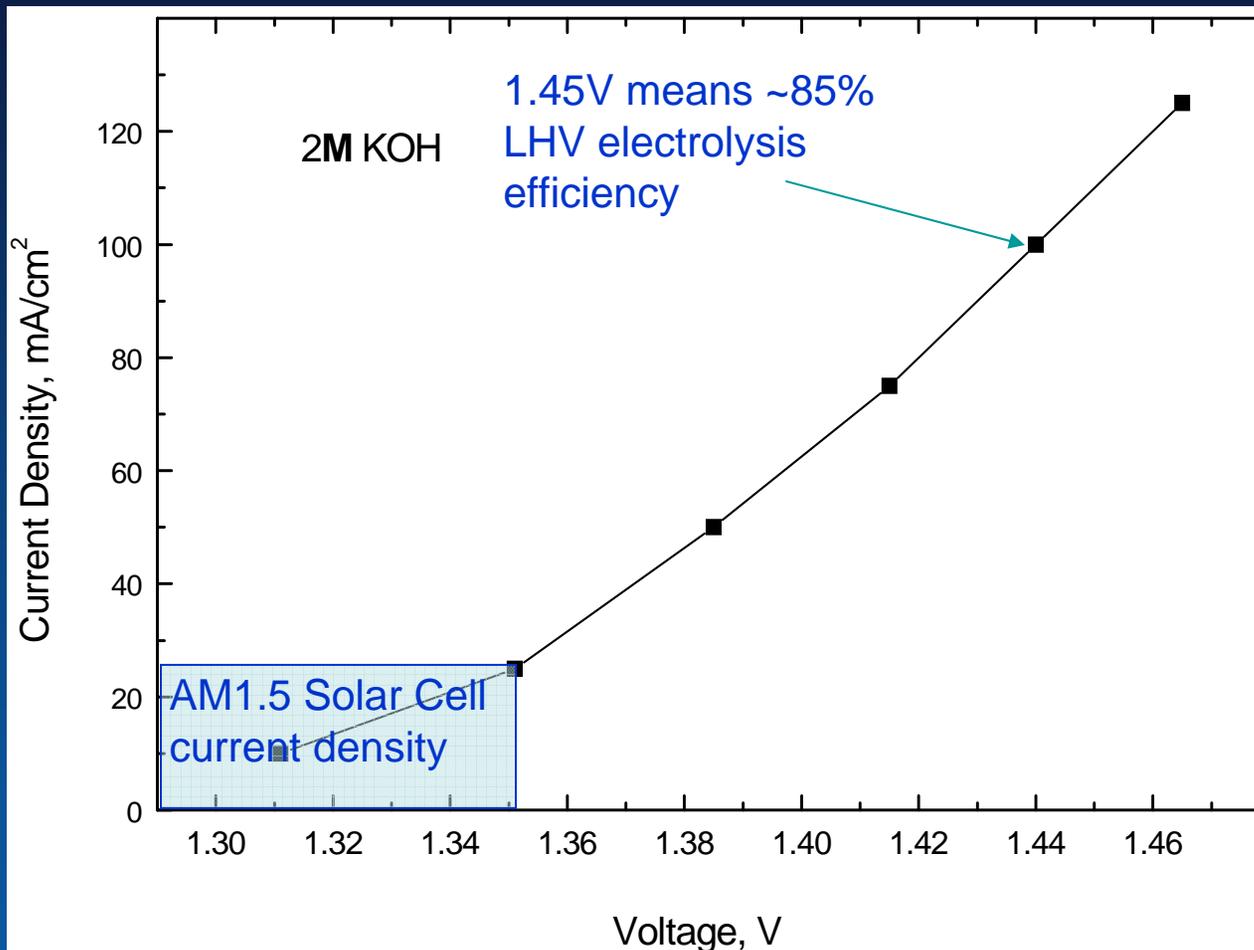
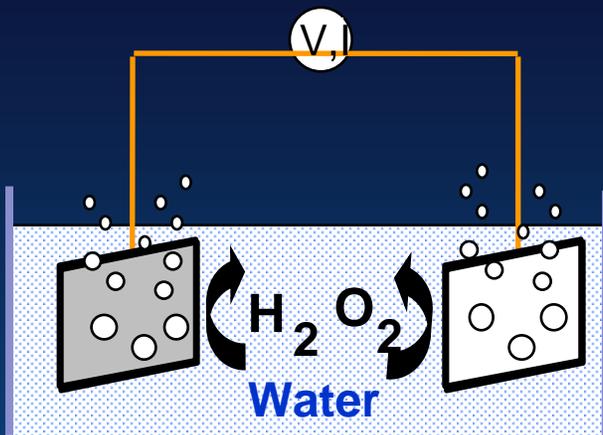
## Goal of the Research



A Monolithic Photoelectrochemical Cell

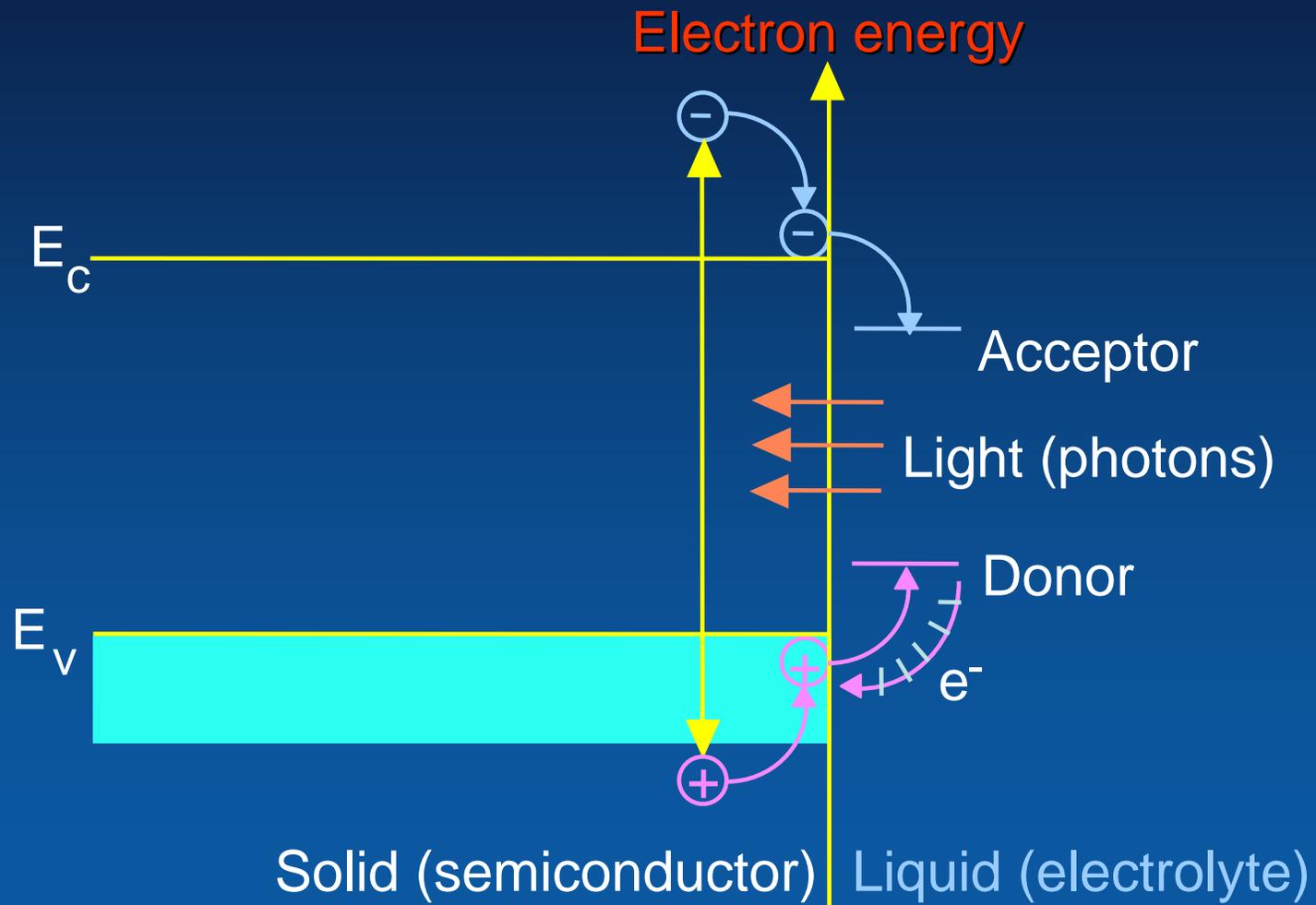
- Combines a photovoltaic system (light harvesting) and an electrolyzer (water splitting) into a single monolithic device.
  - Electrolysis area approximates that of the solar cell - the current density is reduced.
  - Efficiency can be 30% higher than separated system.
- Balance of system costs reduced.
  - Capital cost of electrolyzer eliminated
- Semiconductor processing reduced.

# Current Density vs. Voltage for 2 Pt Electrodes of Equal Area.

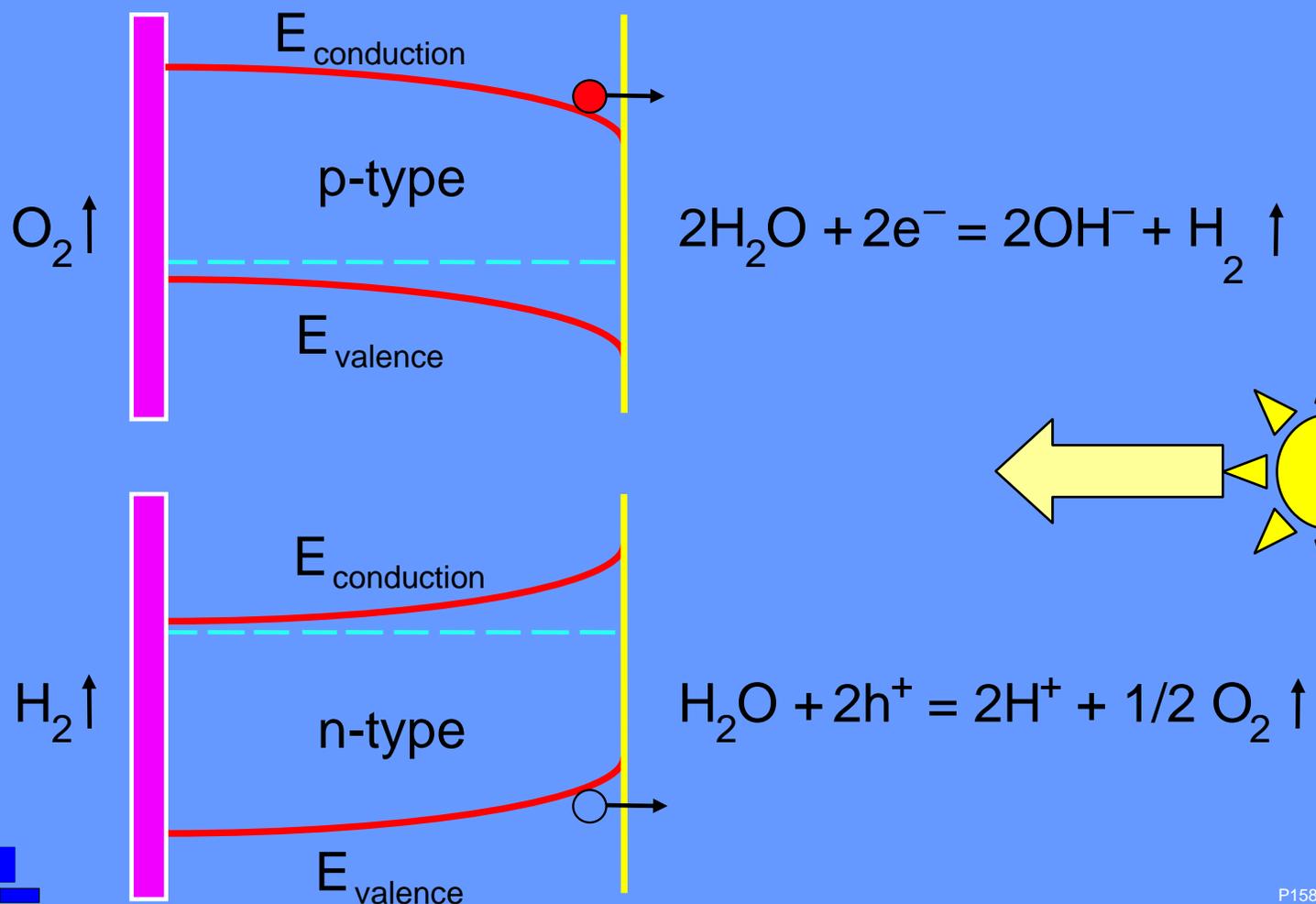


O. Khaselev, A. Bansal and J. A. Turner, *International Journal of Hydrogen Energy*, **26**, p 127-132 (2001).

# Chemical Reactions at a Semiconductor Electrolyte Interphase

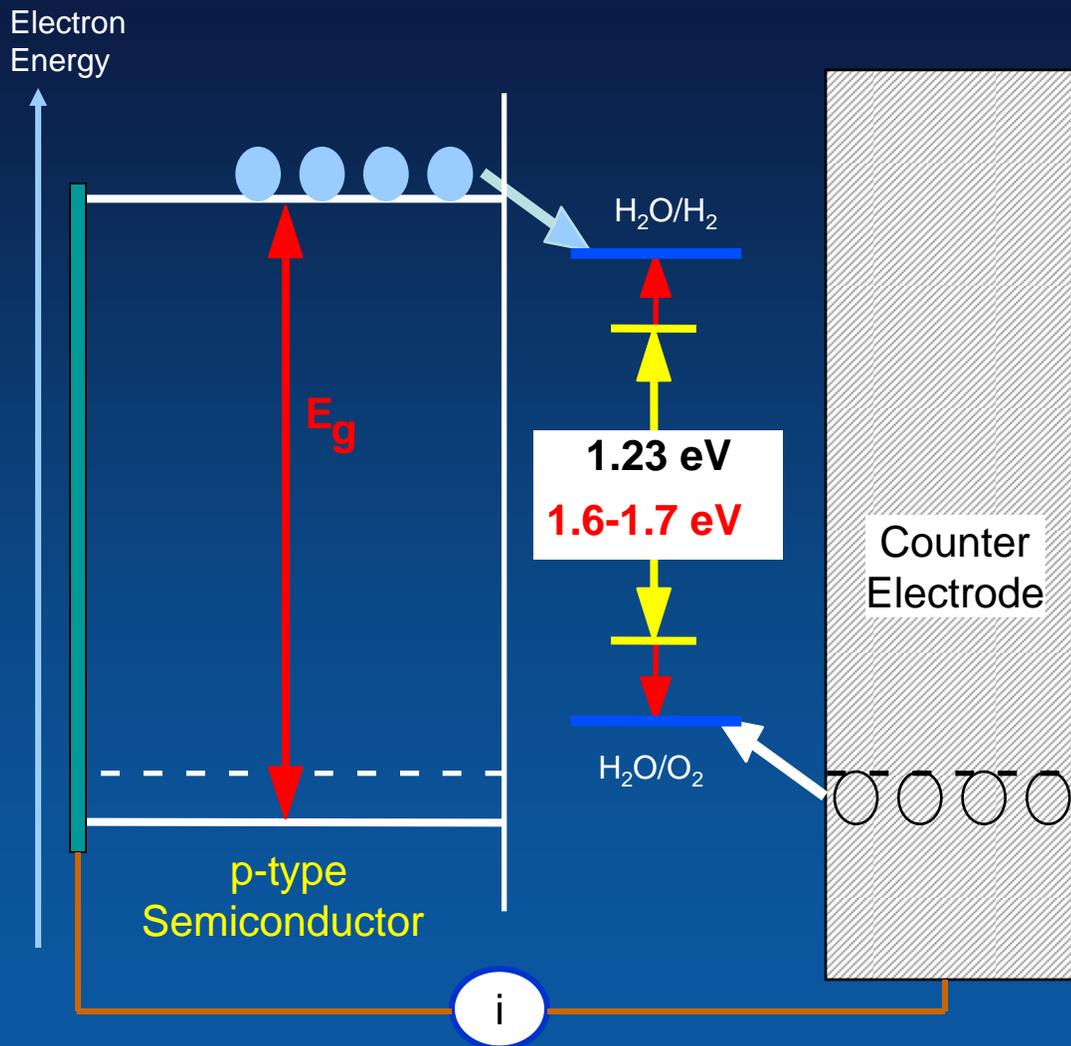


# Band Edges of p- and n-Type Semiconductors Immersed in Aqueous Electrolytes to Form Liquid Junctions



# Technical Challenges *(the big three)*

## Material Characteristics for Photoelectrochemical Hydrogen Production



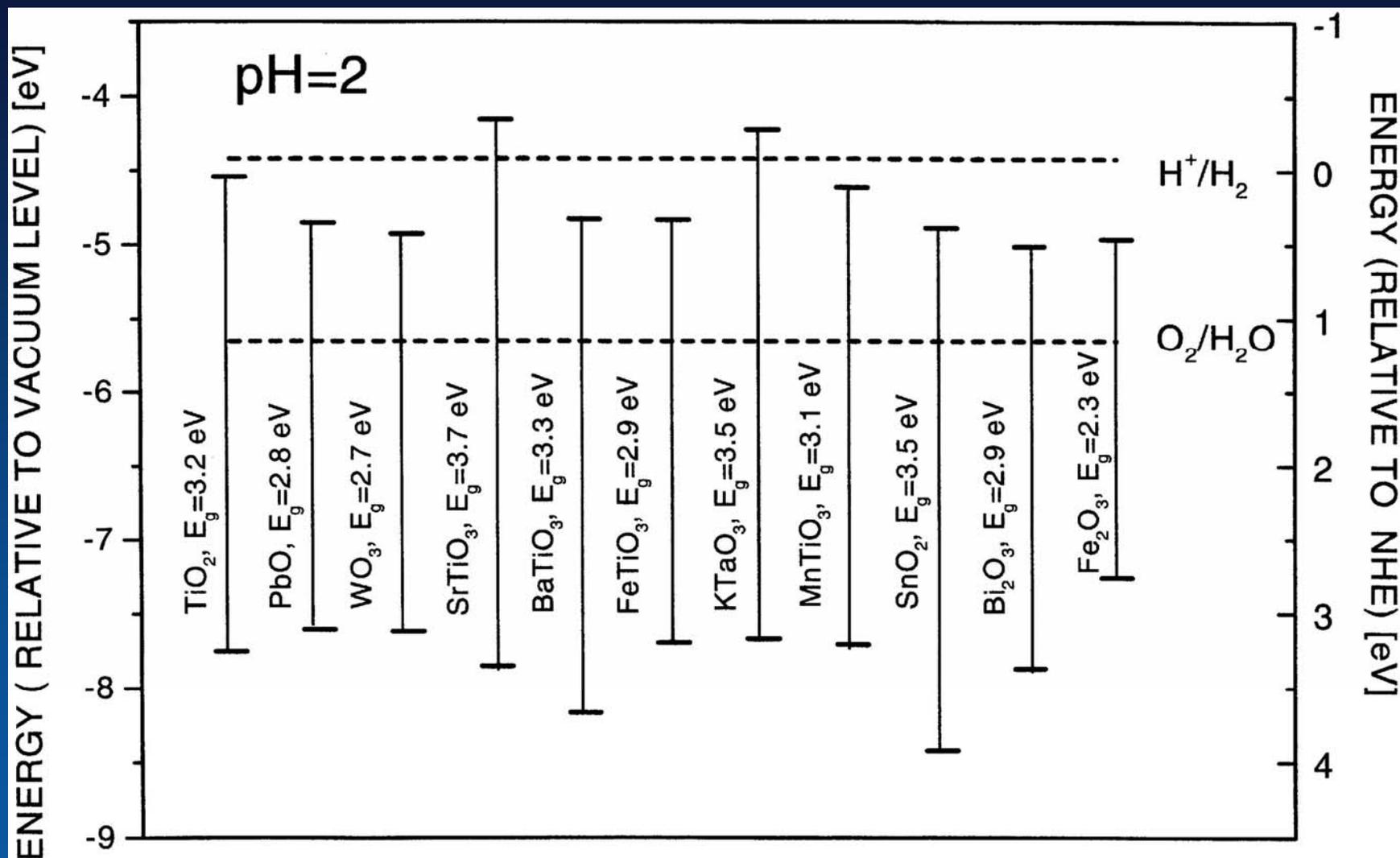
➤ **Efficiency** – the band gap ( $E_g$ ) must be at least 1.6-1.7 eV, but not over 2.2 eV, high photon to electron conversion.

➤ **Material Durability** – semiconductor must be stable in aqueous solution

➤ **Energetics** – the band edges must straddle  $H_2O$  redox potentials (**Grand Challenge**)

All must be satisfied simultaneously

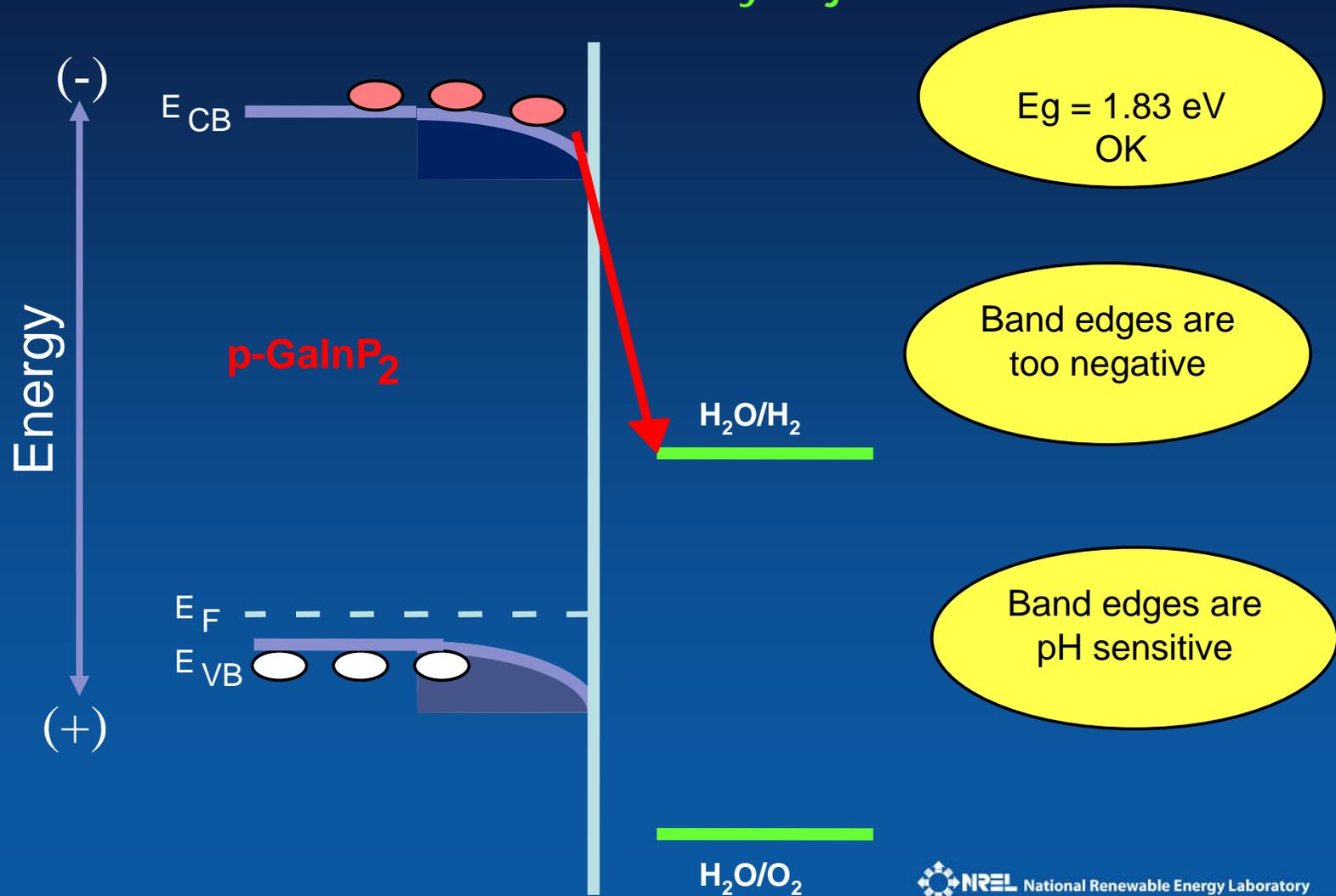
# Bandedge Energetic Considerations



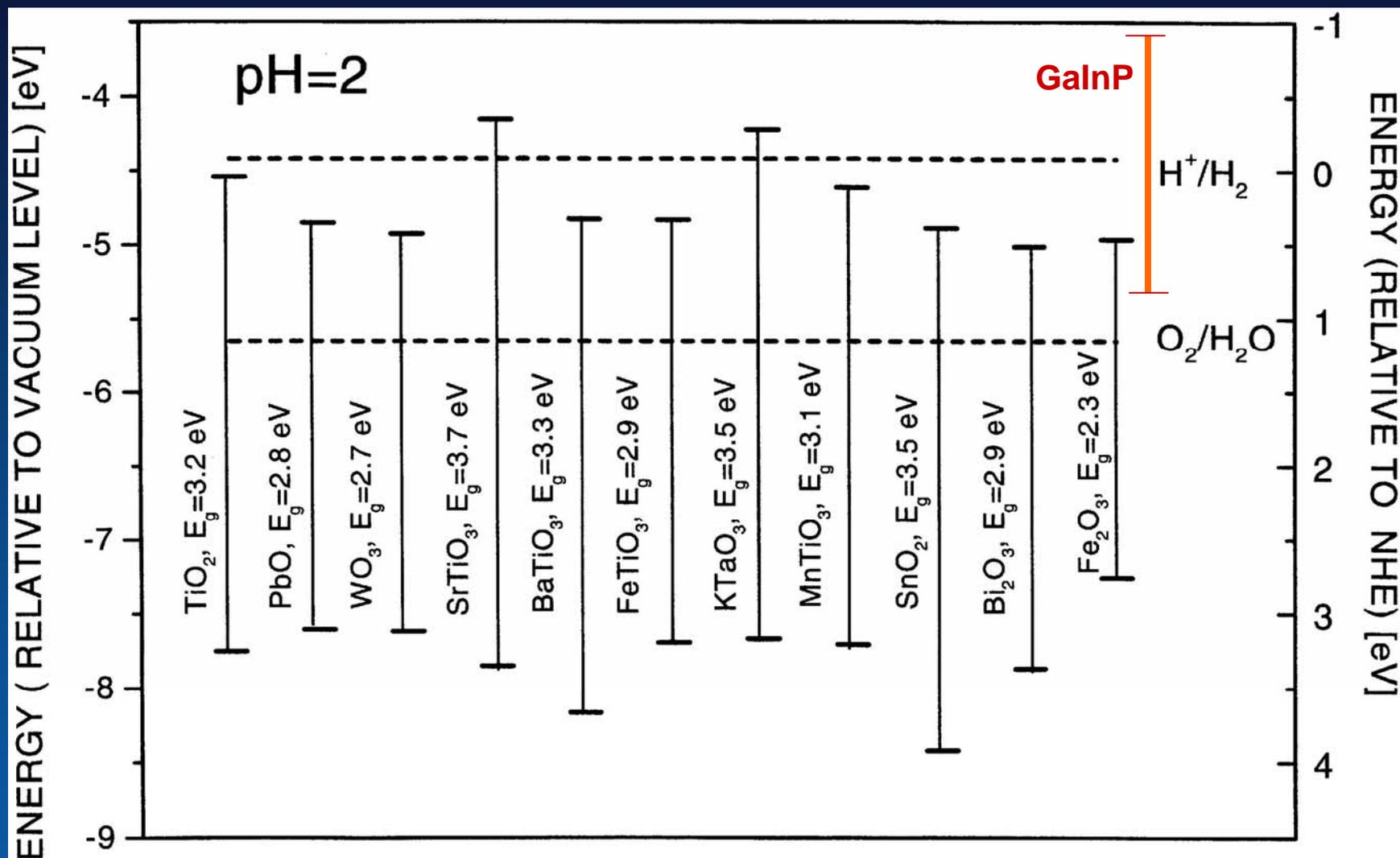
T. Bak, J. Nowotny, M. Rekas, C.C. Sorrell, International Journal of Hydrogen Energy 27 (2002) 991– 1022

# Gallium Indium Phosphide/Electrolyte System

Used to gain a fundamental understanding of semiconductor/electrolyte junctions

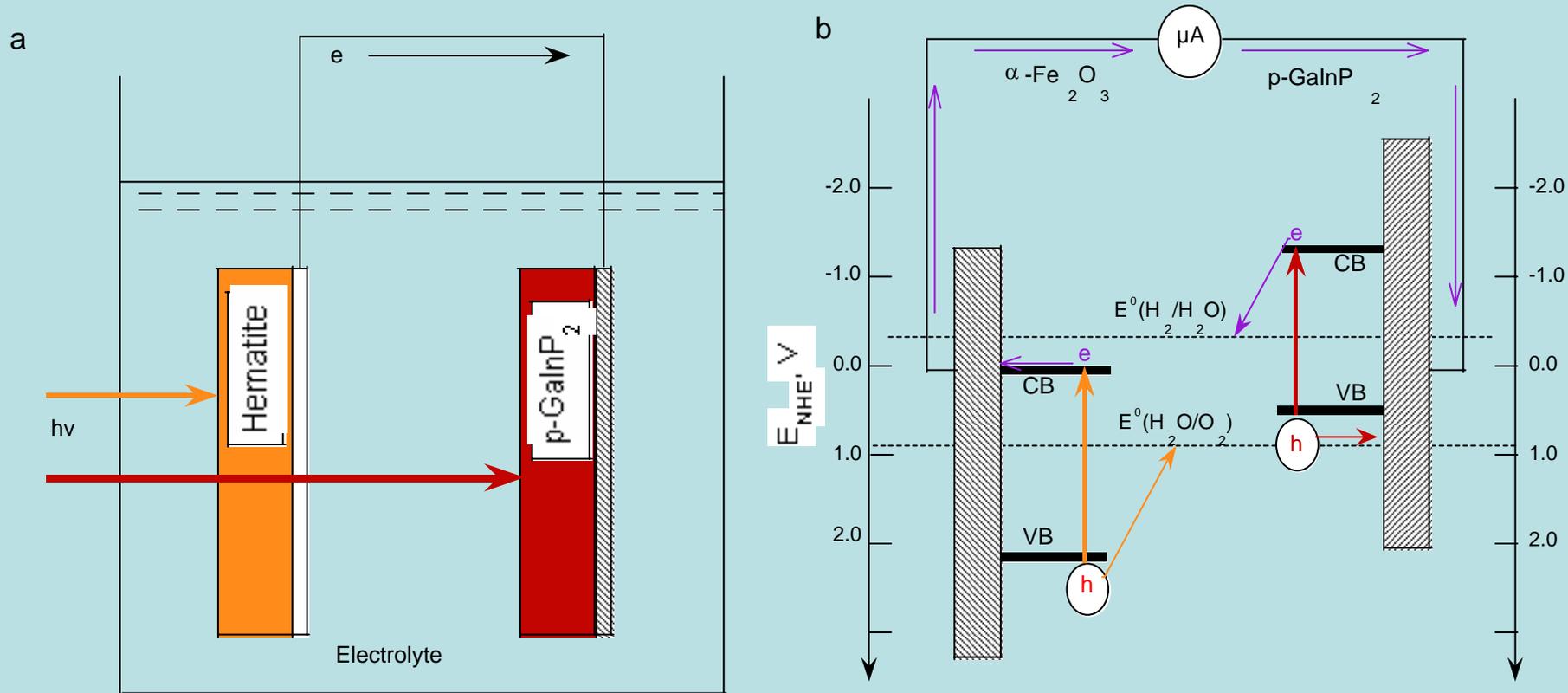


# Bandedge Energetic Considerations



T. Bak, J. Nowotny, M. Rekas, C.C. Sorrell, International Journal of Hydrogen Energy 27 (2002) 991– 1022

# Dual Photoelectrode Approach for Bandedge Mismatch and Stability Issues



Lower cost Fe<sub>2</sub>O<sub>3</sub> electrode is a possibility, but while the system splits water, the efficiency is very low.

# Metal Oxides – A materials assessment

PEC devices must have the same internal photon-to-electron conversion efficiency as PV devices.

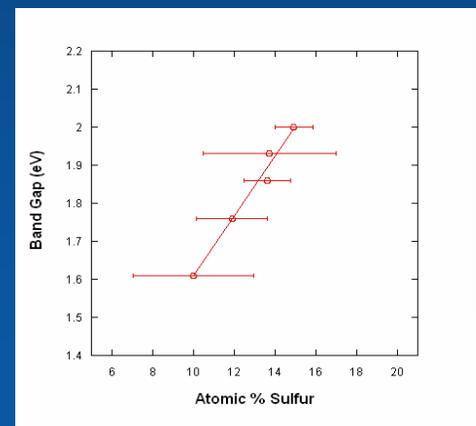
- Transitions which impart color to the oxides typically involve d and f levels and are generally forbidden transitions = **low absorption coefficients**.
  - The low absorption coefficients result in the incident light penetrating deep into the material = **100's um of material**
- Carrier mobilities in oxides are very low
  - **Recombination** of photogenerated carriers occurs before they can reach the semiconductor/electrolyte interface.
- Even good single crystals of metal oxides have very low energy conversion efficiencies due to inherently **short diffusion lengths**.

However a success in this area, e.g. an oxide with good to excellent conversion properties could revolutionize the PV industry as well as make PEC near-term.

# Approach: High Efficiency Materials and Low-Cost Manufacturing

PEC devices must have the same internal photon-to-electron conversion efficiency as commercial PV devices.

- III-V materials have the highest solar conversion efficiency of any semiconductor material
  - Large range of available bandgaps
  - ....but
    - Stability an issue – nitrides show promise for increased lifetime
    - Band-edge mismatch with known materials – tandems an answer
- I-III-VI materials offer high photon conversion efficiency and possible low-cost manufacturing
  - Synthesis procedures for desired bandgap unknown
  - ....but
    - Stability in aqueous solution?
    - Band-edge mismatch?
- Other thin-film materials with good characteristics
  - SiC: low cost synthesis, stability
  - SiN: emerging material



# Approach: Materials Summary

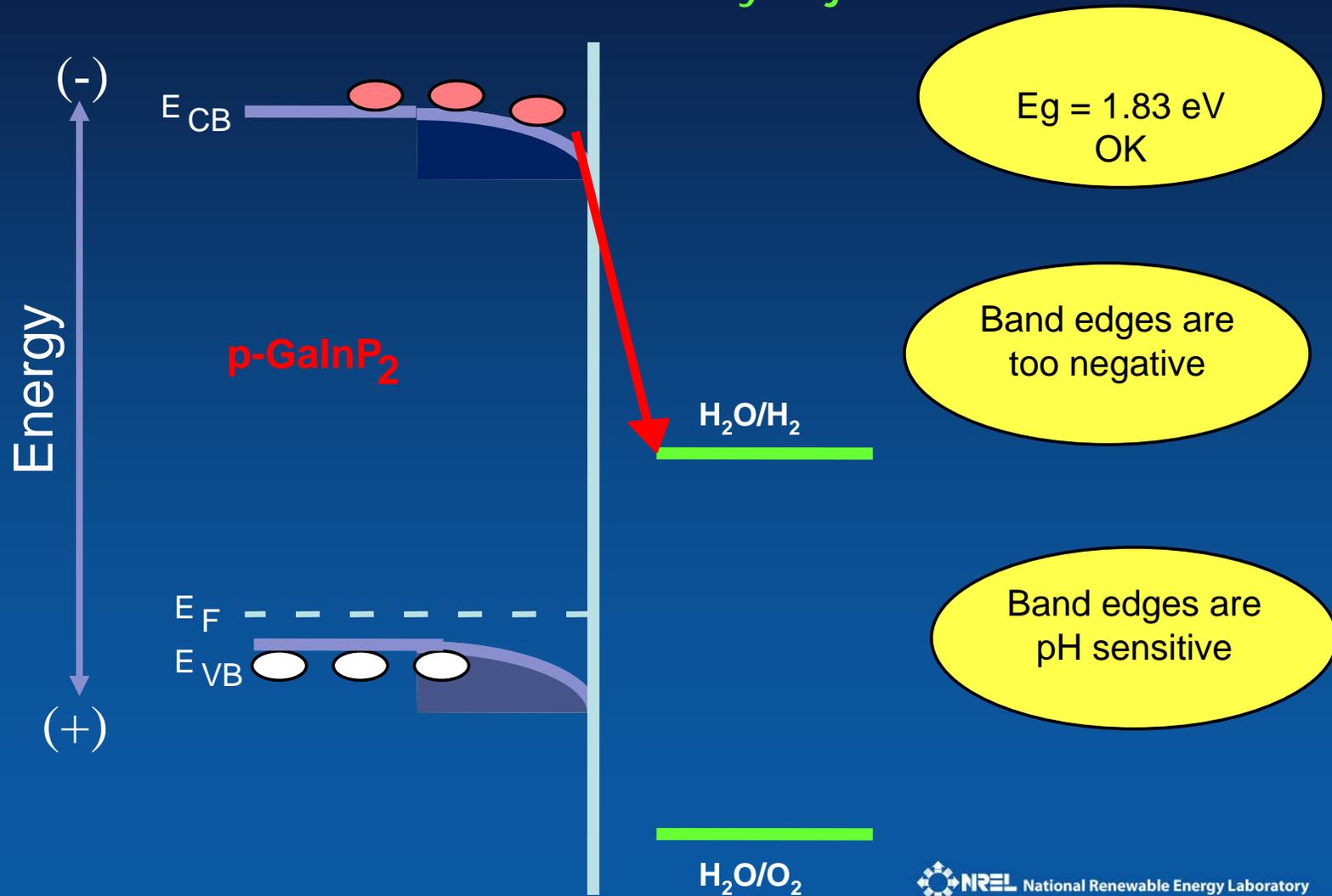
The primary task is to synthesize the semiconducting material or the semiconductor structure with the necessary properties. This involves material research issues (material discovery), multi-layer design and fabrication, and surface chemistry. Activities are divided into the task areas below – focus areas in **Green**:

- ✓ *GaPN - NREL (high efficiency, stability)*
- ✓ *CuInGa(Se,S)<sub>2</sub> - UNAM (Mexico), NREL (Low cost)*
- ✓ *Silicon Nitride – NREL (protective coating and new material)*
- ✓ GaInP<sub>2</sub> - NREL (fundamental materials understanding)
- ✓ Energetics
  - ✓ Band edge control
  - ✓ Catalysis
  - ✓ Surface studies

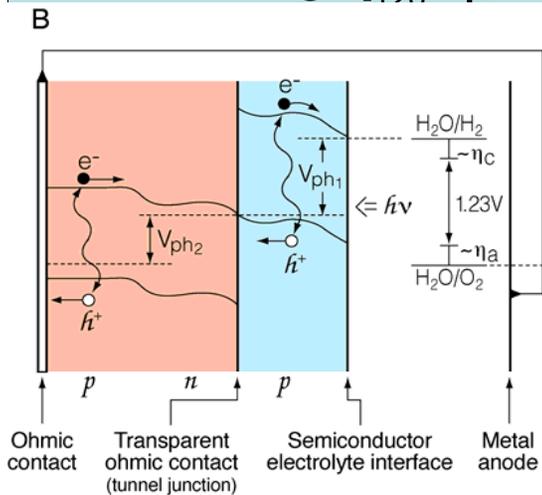
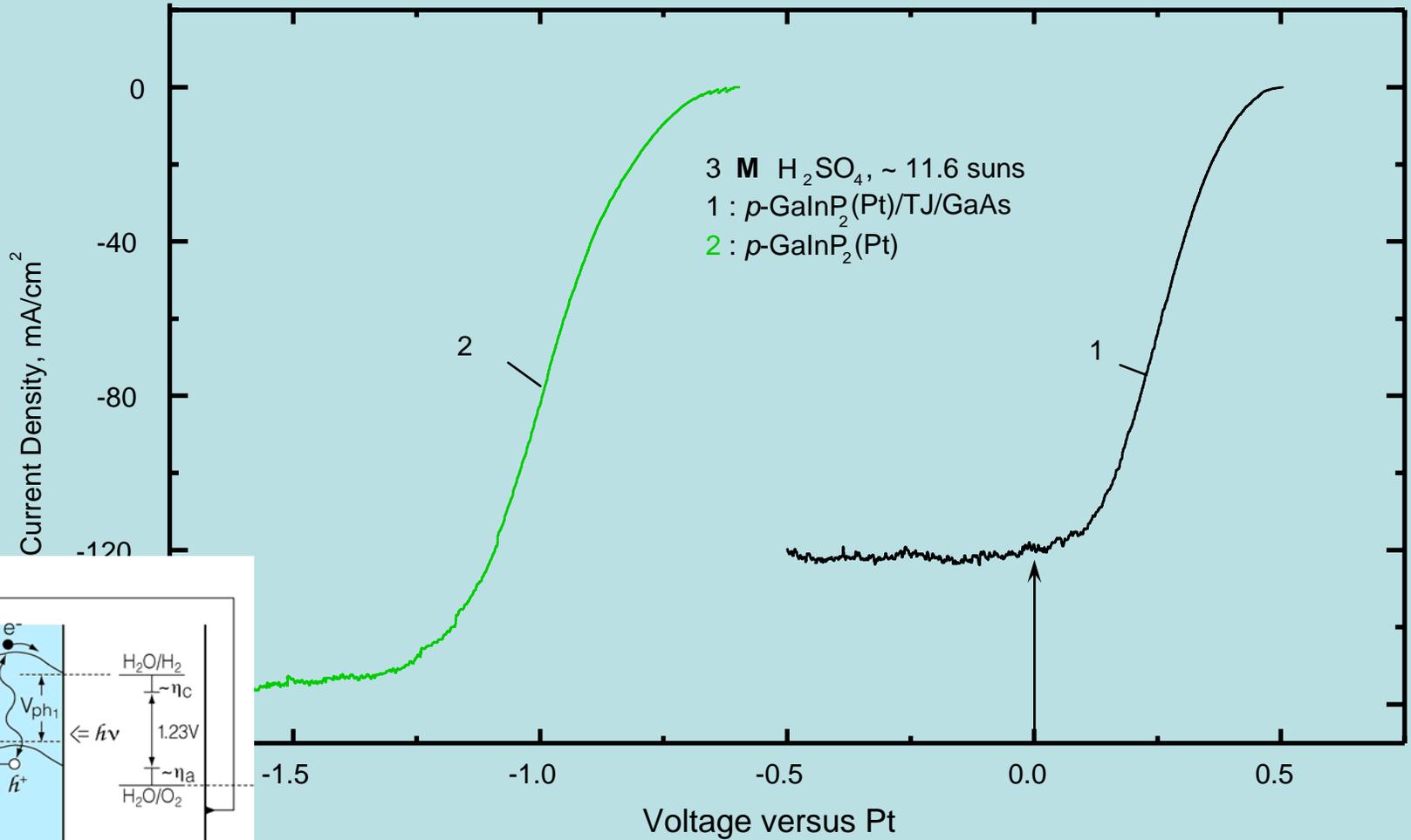


# Gallium Indium Phosphide/Electrolyte System

Used to gain a fundamental understanding of semiconductor/electrolyte junctions



# Review: Comparison of $p\text{-GaInP}_2$ and PEC/PV device



The GaAs integrated PV cell compensates for the energetic mismatch – but lifetime...

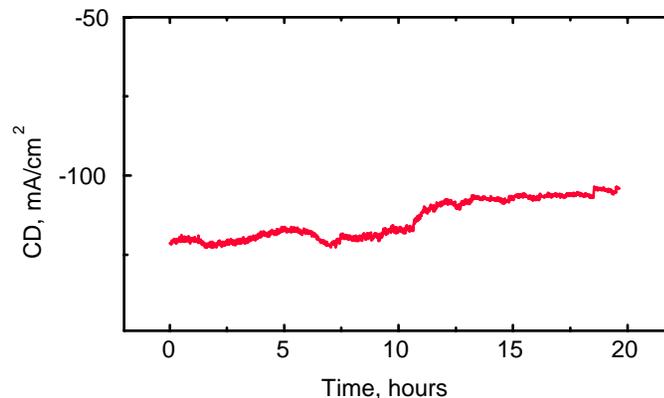
# Photocurrent time profile for PEC/PV Water-Splitting device, showing current decay due to corrosion.

O. Khaselev and J. A. Turner, Science, **280**, pg 425 (1998).



Current Density, mA/cm<sup>2</sup>

-80  
-100  
-120  
-140



We are looking for materials with inherently greater stability.

$$\text{Efficiency}(\%) = (120\text{mA/cm}^2 * 1.23\text{v} / 1190\text{ mW/cm}^2) * 100 = \underline{12.4\%}$$

0

500

1000

1500

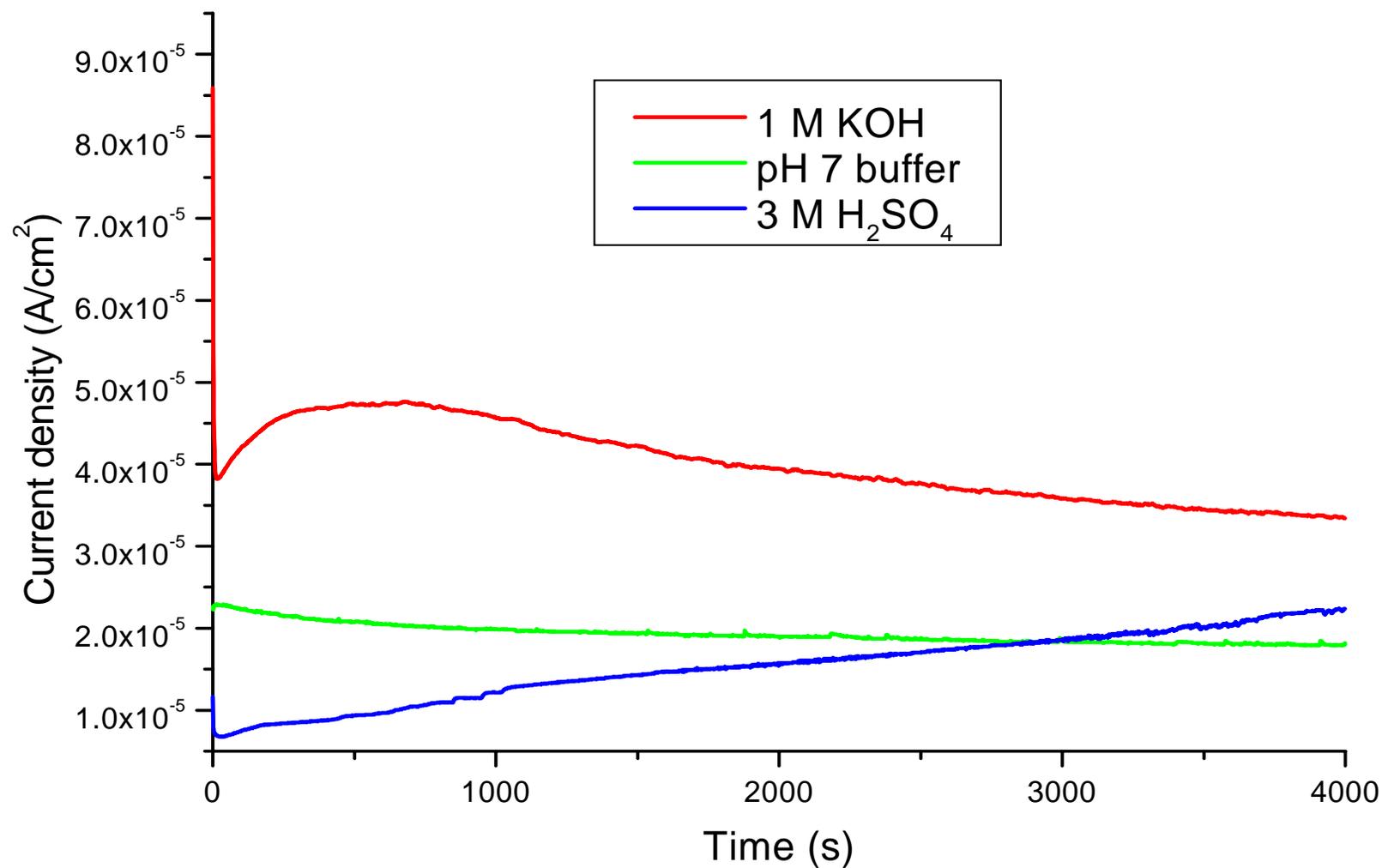
Time, sec

# Elemental Abundances in Earth's Crust

Element	Concentration (mg/kg)	Element	Concentration (mg/kg)
Gallium	19	P	1050
Lead	14	Silicon	$2.8 \times 10^5$
Boron	10	Indium	0.25
Lithium	20	Silver	0.075
Tungsten	1.25	Tin	2.3
Cobalt	25	Uranium	2.7

Gallium is found in bauxite (aluminum ore). There are 2 million kg of Ga in Arkansas bauxite deposits alone. Also found in coal ash (up to 1.5%).

# Hydrogen Evolution Current-Time Profile for p-GaN



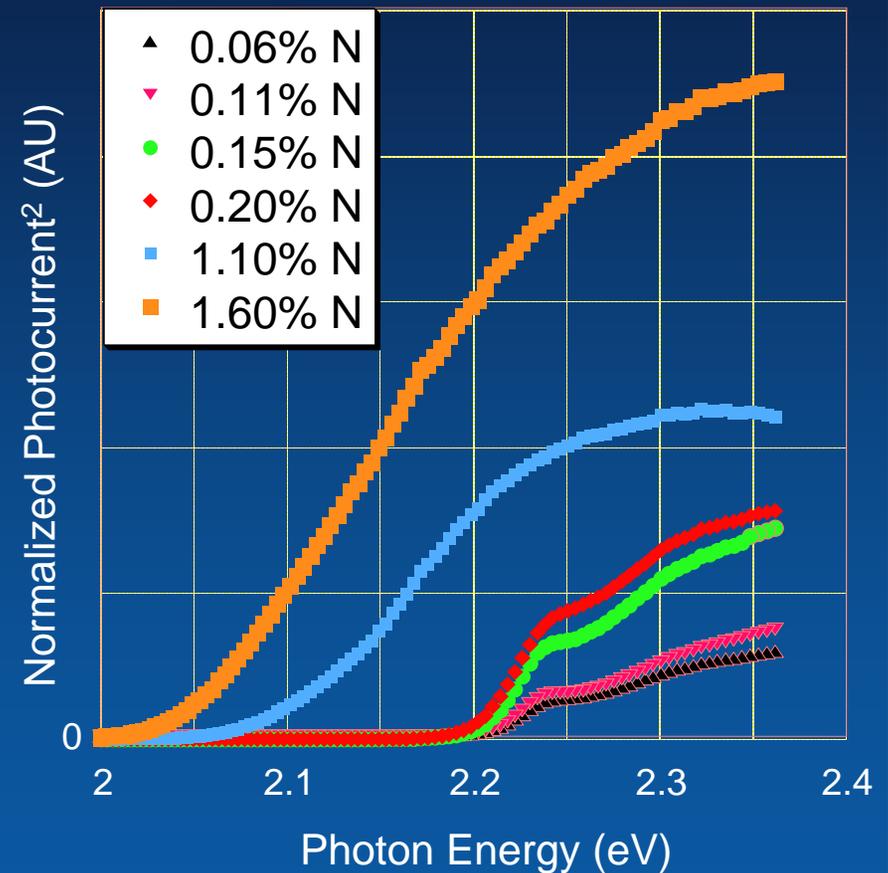
S. Kocha, M. Peterson, D. J. Arent, J. M. Redwing, M. A. Tischler and J. A. Turner, "Electrochemical Investigation of the Gallium Nitride-Aqueous Electrolyte Interface", *Journal of The Electrochemical Society*, 1995, 142, pg. L236-L240.

Goal: Stable III-V nitride material

## III-V Nitrides for PEC Water Splitting Systems: $\text{GaP}_{1-x}\text{N}_x$

- GaN
  - Capable of water-splitting and stable
  - Band gap direct but too wide (~3.4 eV)
- GaP
  - Band edges almost aligned
  - Band gap indirect and too wide (~2.3 eV), but better
- $\text{GaP}_{1-x}\text{N}_x$ 
  - Addition of small amounts of N causes GaP band gap to narrow (bowing) and transition to become direct
  - Nitrogen enhances stability

$\text{GaP}_{1-x}\text{N}_x$  Epilayer Direct Band Gap



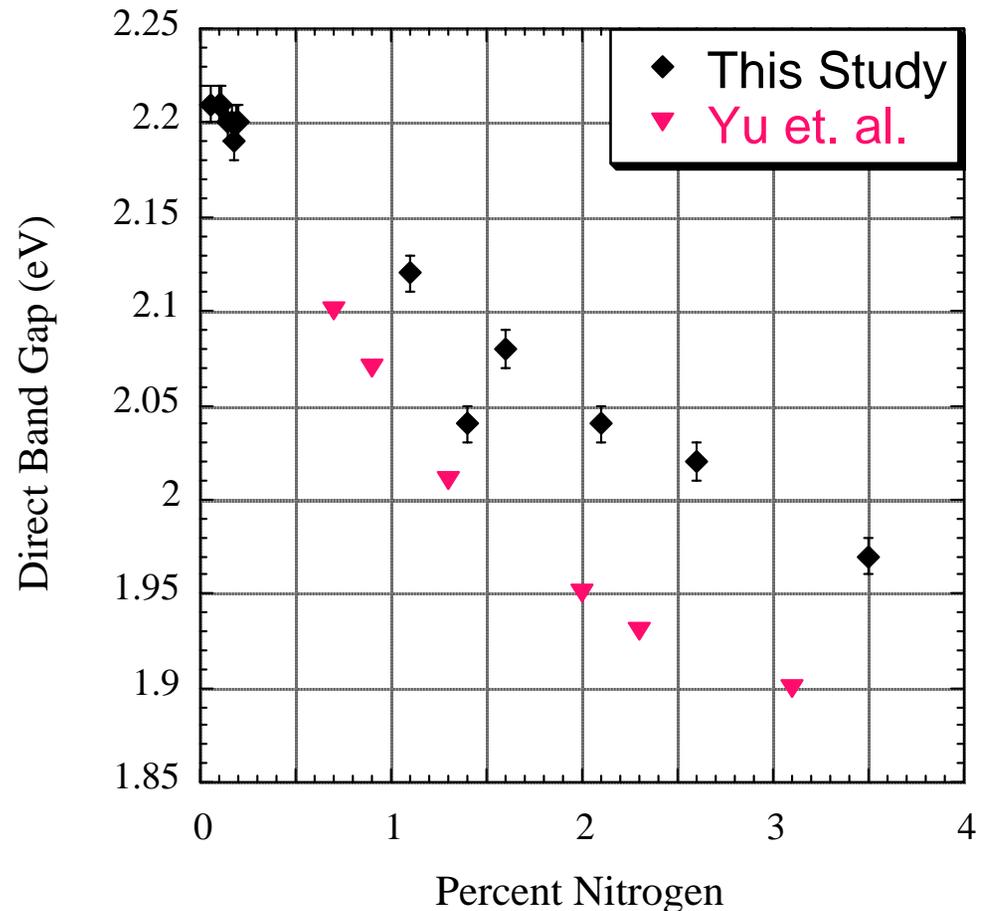
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# GaP<sub>1-x</sub>N<sub>x</sub> Bandgap as a Function of Nitrogen Concentration

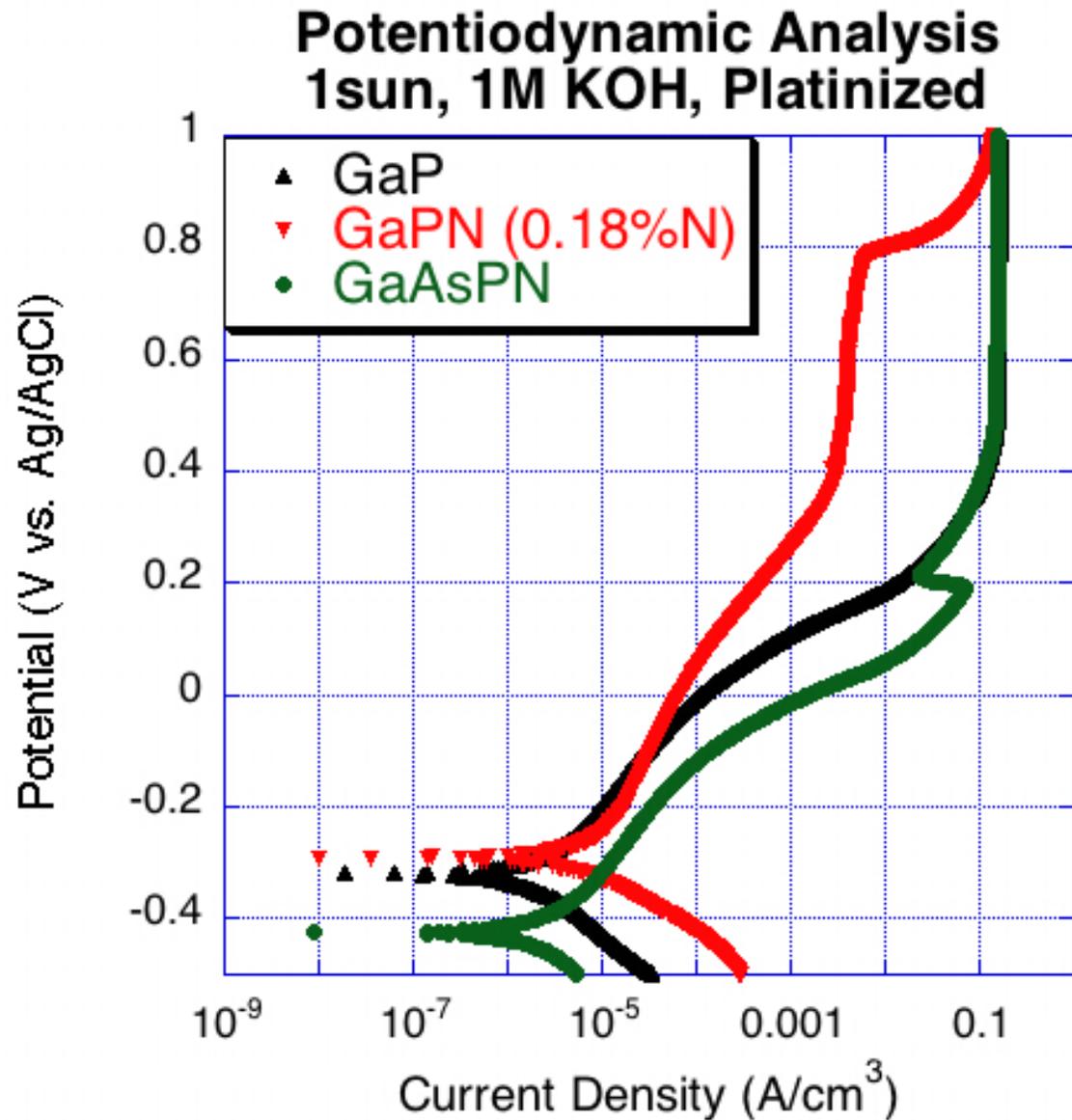
- Control band gap energy by varying nitrogen composition,
- Direct band gap for all nitrogen concentrations, even at GaP<sub>.9994</sub>N<sub>.0006</sub>
- The crossover from indirect to direct occurs significantly below the theoretically predicted 0.26%

(F. Benkabou, J. P. Becker, M. Certier, H. Aourag, Calculation of Electronic and Optical Properties of Zinc Blende GaP<sub>1-x</sub>N<sub>x</sub>. Superlattices and Microstructures, 1998. 23(2): p. 453-465.)



K.M. Yu, W. Shan, J. Wu, Nature of the fundamental band gap in Ga<sub>x</sub>P<sub>1-x</sub> alloys. Applied Physics Letters, 2000. 76(22): p. 3251-3253

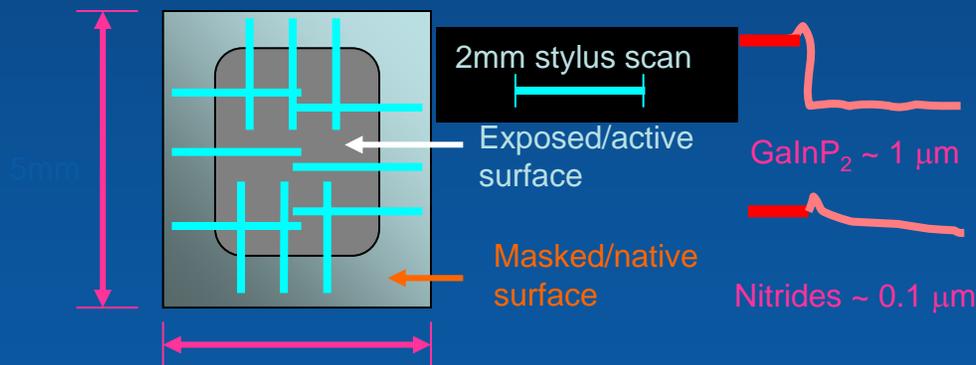
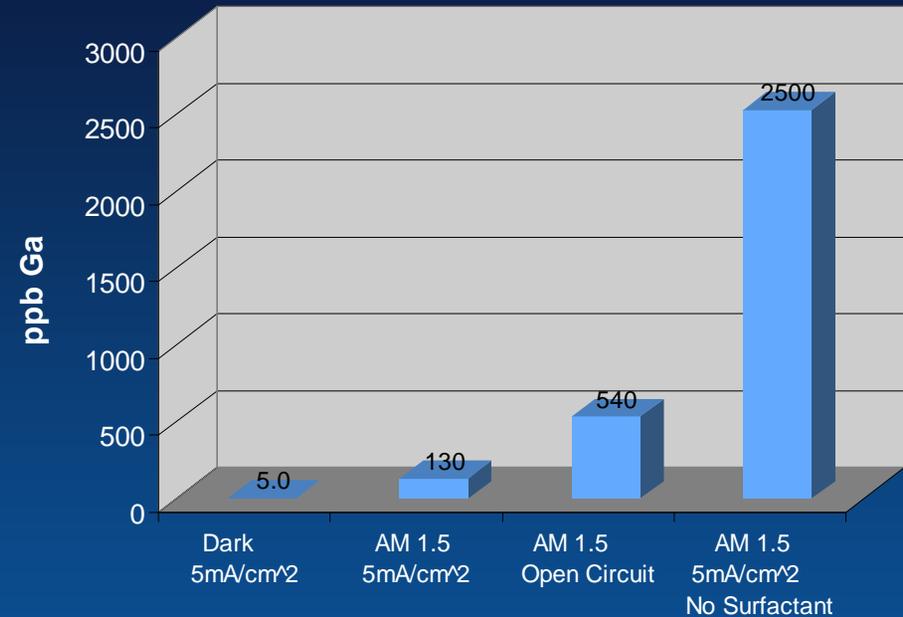
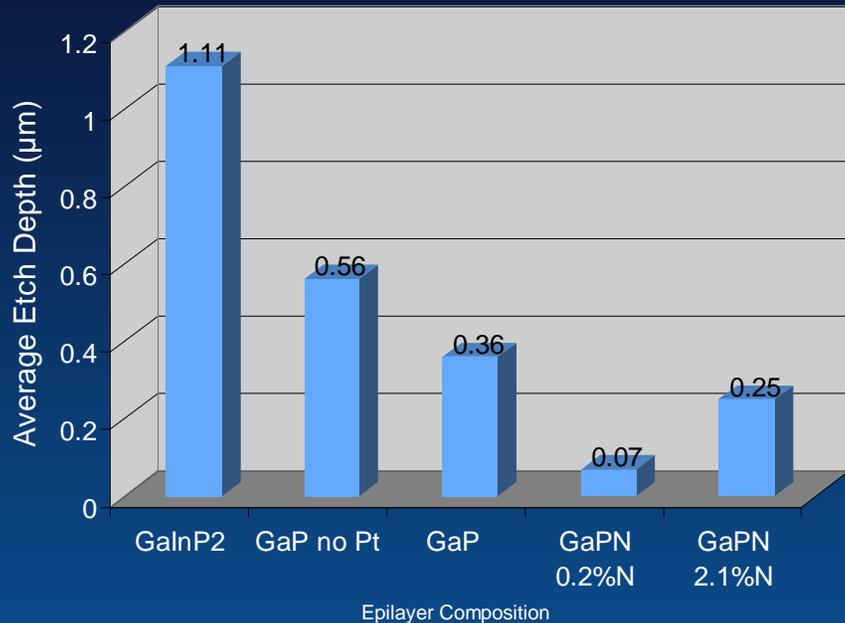




Corrosion experiments on GaP substrate clearly show the enhanced corrosion resistance from nitrogen addition.



# GaPN Stability Measured by Profilometry and by ICP-MS of Solution



## Conditions

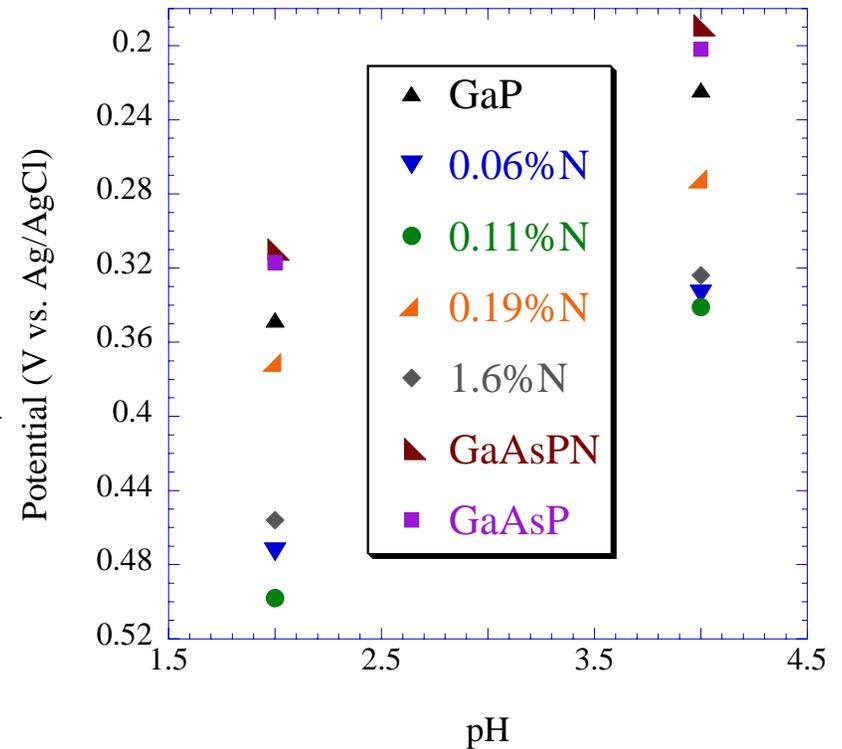
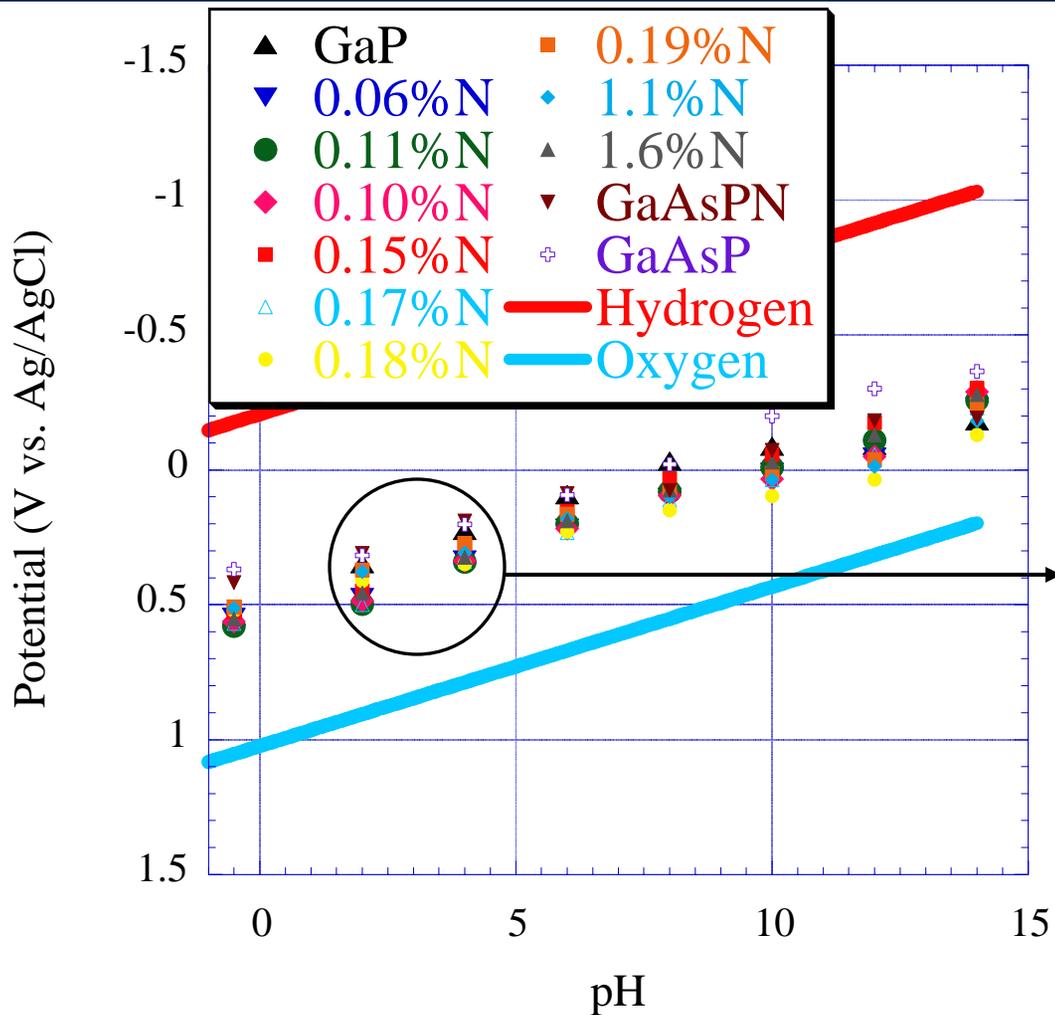
- Photocathode durability testing
  - 5mA/cm<sup>2</sup>, AM 1.5, 24 hours, 3M H<sub>2</sub>SO<sub>4</sub>, pulsed Pt treatment
  - Ga content of solutions by ICP-MS
  - Etching by profilometry
- Represents ~300 hrs of stability for 1 µm layer



Goal: Stable III-V nitride material

# Band Edge Energetics

The band edges of these materials are too negative for spontaneous water-splitting.



# Approach: Two configurations

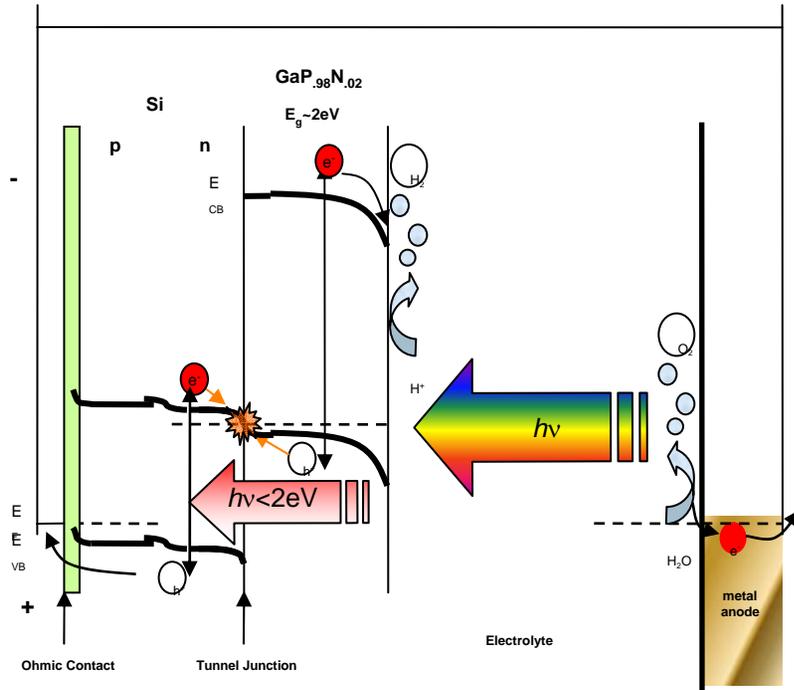
One for material study and one for possible high-efficiency tandem cell.

- GaPN/tj/ p-GaP or n-silicon substrate
  - Undoped
  - No low energy transition expected
- GaPN/tj/ p/n silicon substrate (tandem)
  - Undoped
  - Low energy transition expected

1 $\mu\text{m}$ i-GaP.9806N.0194	1 $\mu\text{m}$ p-GaP.9818N.0182
0.04 $\mu\text{m}$ GaP	0.04 $\mu\text{m}$ GaP
n-Si substrate	n-Si
Ti/Pd/Al/Pd/Au Ohmic contact	p-Si substrate
	Al Ohmic contact
MF097	MF098



Goal: Stable III-V nitride material



# GaPN:Si Tandem Cell

- ~ 1% water splitting efficiency
- Results complicated by compositional variation across the sample

Direct  $E_g$  (eV)  
Nitrogen%

1.99 2.2%	2.00 2.1%	2.00 2.1%	2.01 2.0%	2.01 2.0%
2.00 2.1%	2.01 2.0%	2.01 2.0%	2.02 1.9%	2.02 1.9%
2.01 2.0%	2.02 1.9%	2.02 1.9%	2.02 1.9%	2.03 1.8%
2.03 1.8%	2.03 1.8%	2.03 1.8%	2.03 1.8%	2.04 1.7%

Tunnel Junction

1  $\mu\text{m}$  p-GaP<sub>.98</sub>N<sub>.02</sub>

0.15  $\mu\text{m}$  p+ GaP

0.7  $\mu\text{m}$  n+ GaPN

0.04  $\mu\text{m}$  GaP buffer

0.2  $\mu\text{m}$  n-Si (P diff)

p-Si Substrate

Al Ohmic contact

20mm

25mm

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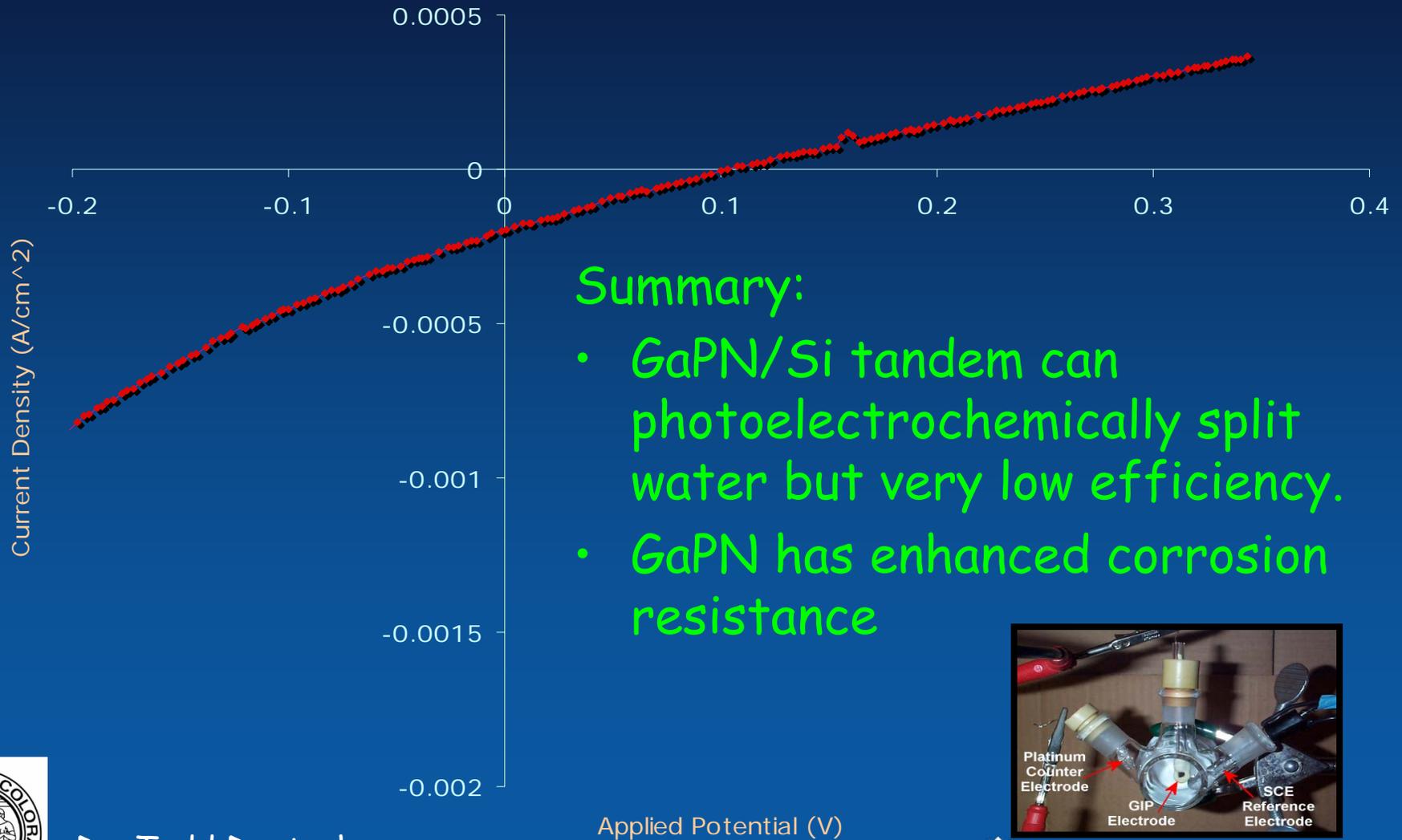


National Renewable Energy Laboratory

Goal: Stable III-V nitride material

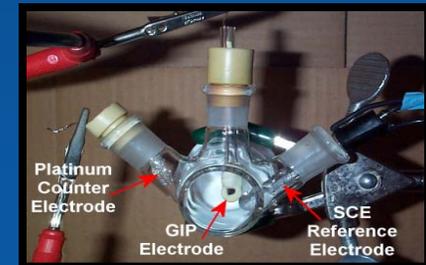
# Light-Driven Water Splitting

MF771-4 2-electrode J-V in acid 1 sun illumination



## Summary:

- GaPN/Si tandem can photoelectrochemically split water but very low efficiency.
- GaPN has enhanced corrosion resistance

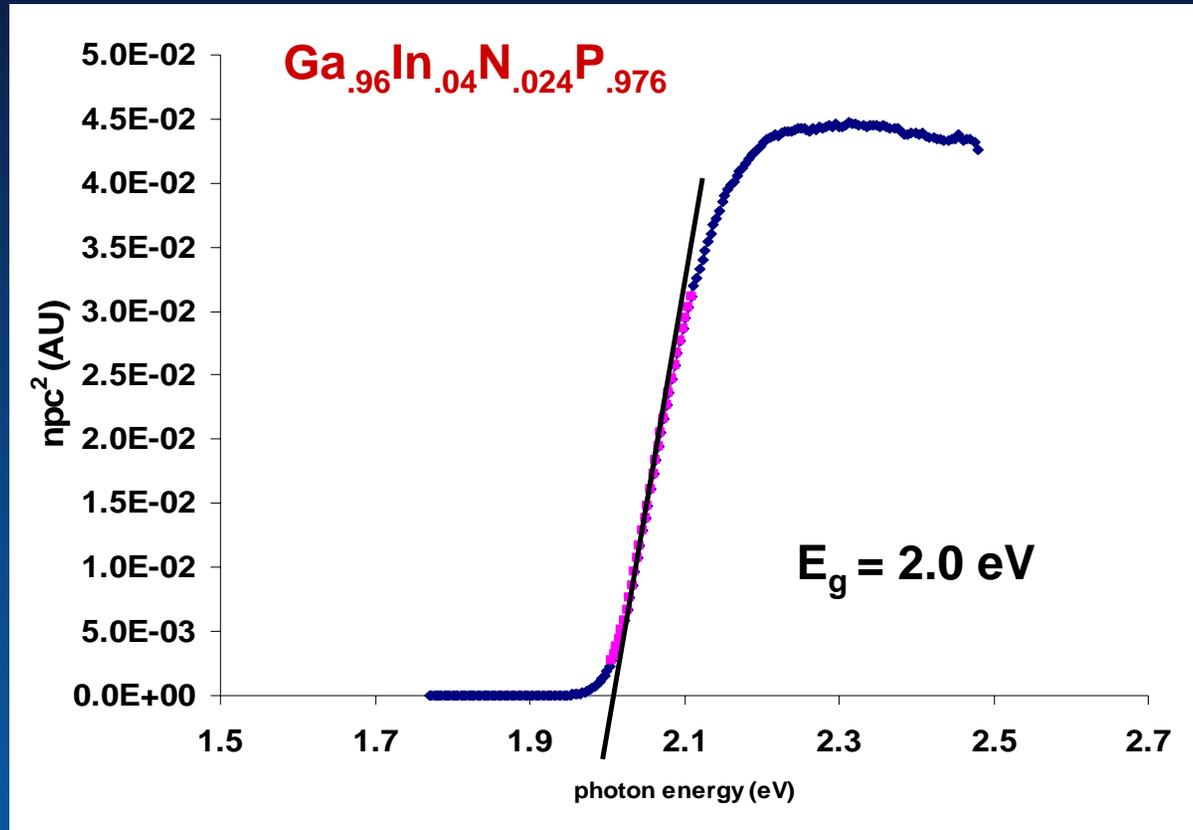
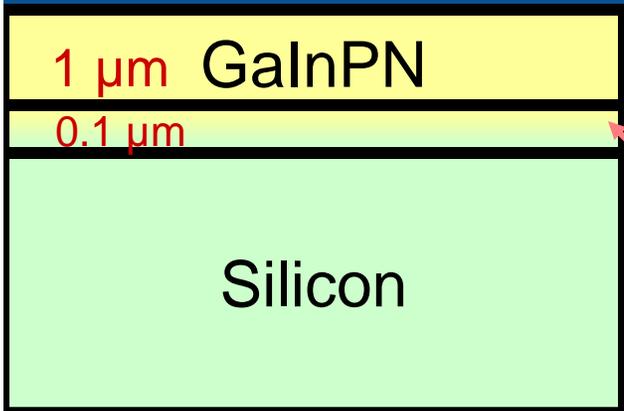
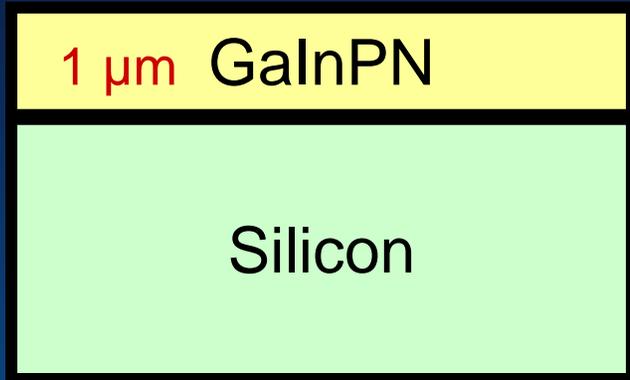


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Applied Potential (V)

Goal: Stable III-V nitride material

# GaInPN:Si – Two Tandem Cell Configurations



Zn-doped GaInPN

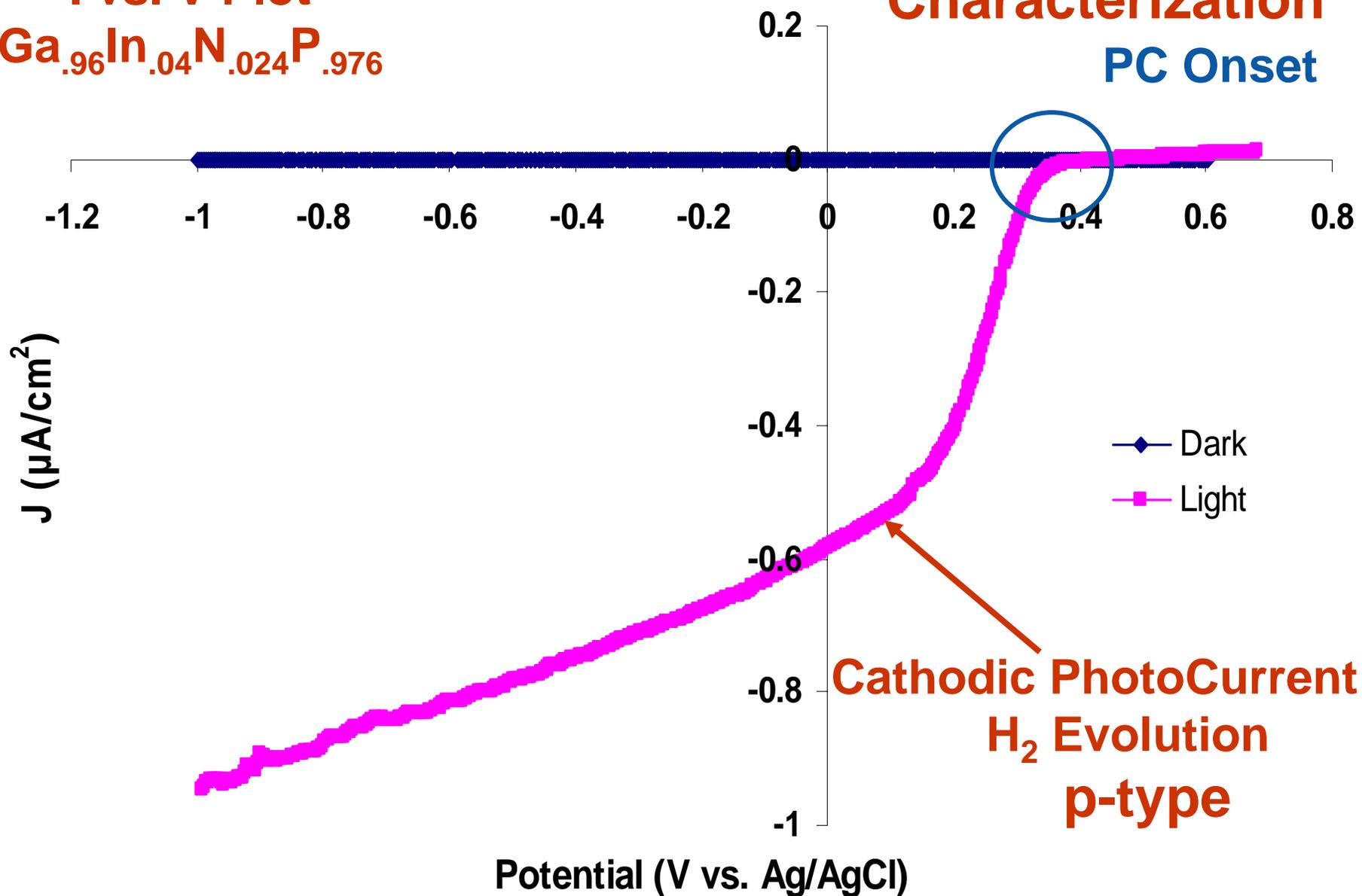
Jeff Head, Paul Vallett

# I vs. V Plot

$\text{Ga}_{.96}\text{In}_{.04}\text{N}_{.024}\text{P}_{.976}$

# Characterization

## PC Onset



Goal: Stable III-V nitride material

## Stability by Profilometry



Etched: 0.13 $\mu\text{m}$ /24hrs

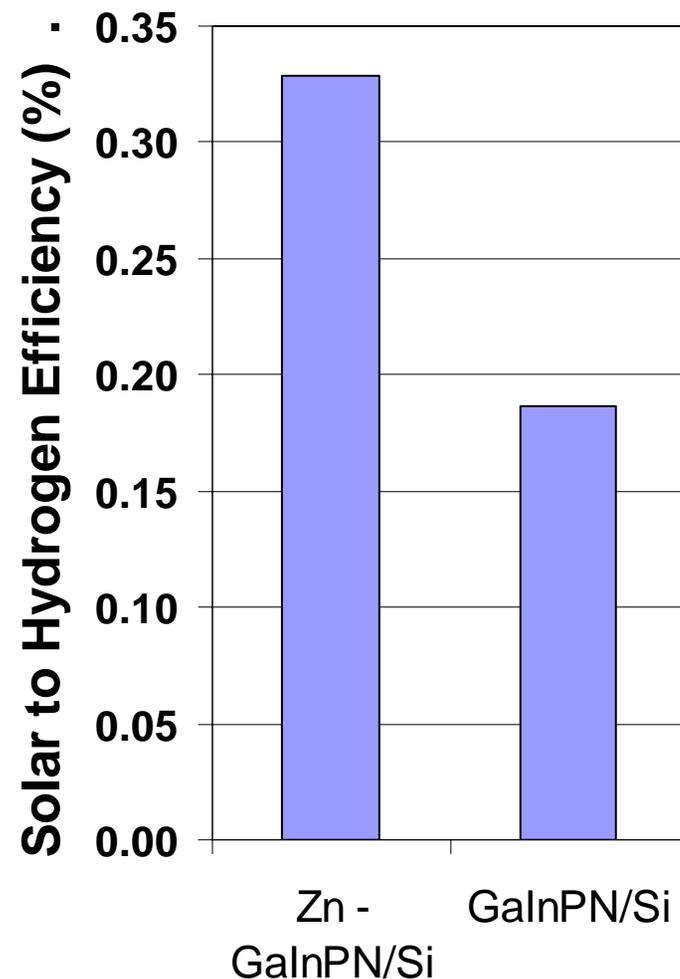


Etched: 0.14 $\mu\text{m}$ /24hrs

$\text{GaInP}_2$ : 1-2 $\mu\text{m}$ /24hrs

# Water Splitting

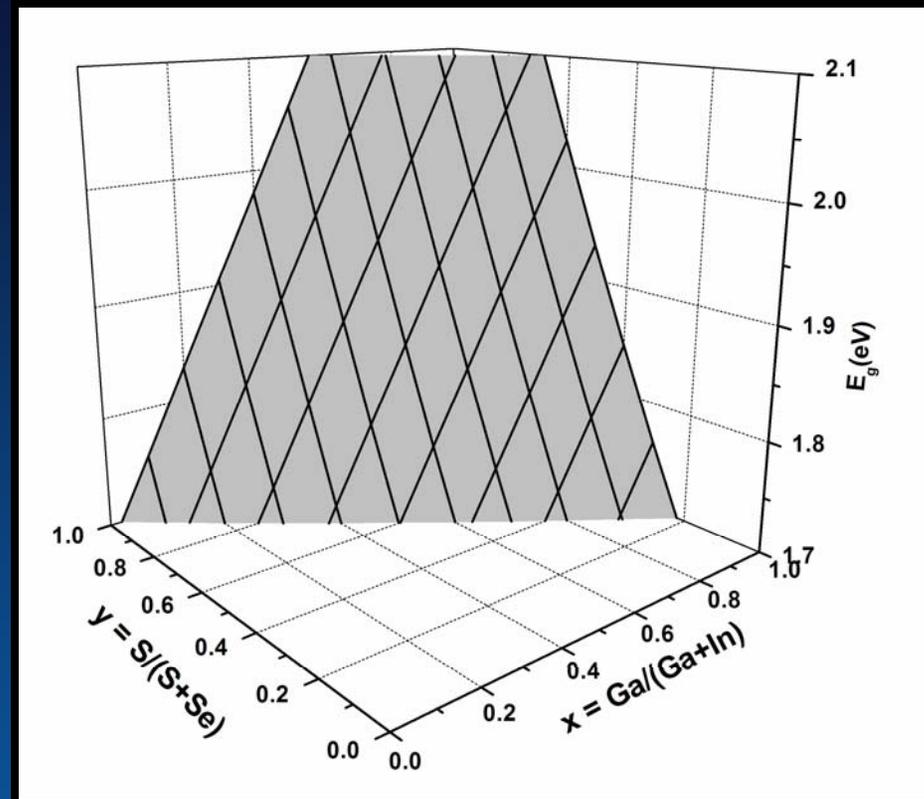
- Photon to chemical energy conversion efficiency
  - GaInPN: ~30%
  - GaInP<sub>2</sub>: ~90%
- Zn-doped layer improves efficiency
- Nitrogen decreases electronic properties of material



Goal: Evaluation of high efficiency thin-film CIS-based material

## Electrodeposited CIGSS

- CIS material system:  $\text{CuInSe}_2 - \text{CuGaSe}_2$ 
  - $E_g$  range: 1.0 – 2.5eV
- $\text{CuGaSe}_2$ :  $E_g = \sim 1.7$
- High PV efficiencies in this system
- Potential low cost, low energy deposition
- Two configurations:
  - Single materials
  - As a layer in a multijunction system



Relationship of bandgap to alloy composition. Gray area represents compositions that produce bandgaps in the range 1.7 - 2.1eV

Goal: Evaluation of high efficiency thin-film material and thin-film based tandem cell

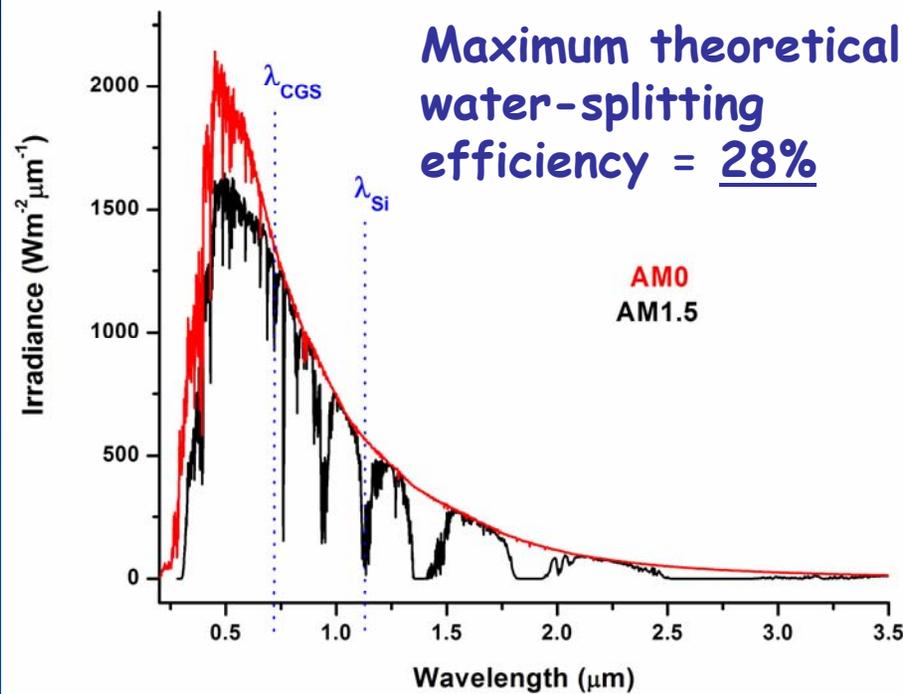
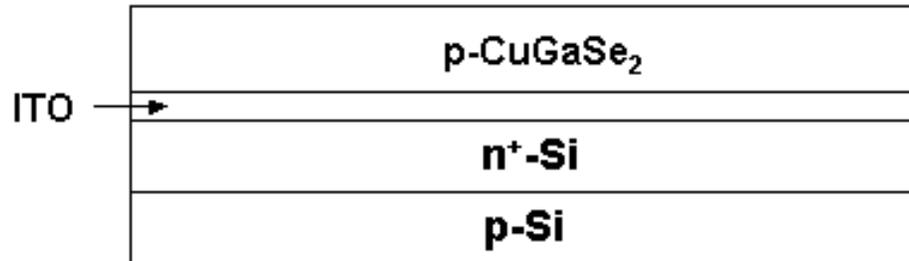


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Goal: Thin-film based PEC tandem cell

# Tandem Cell Configuration

## CGS Grown by Thermal Evaporation

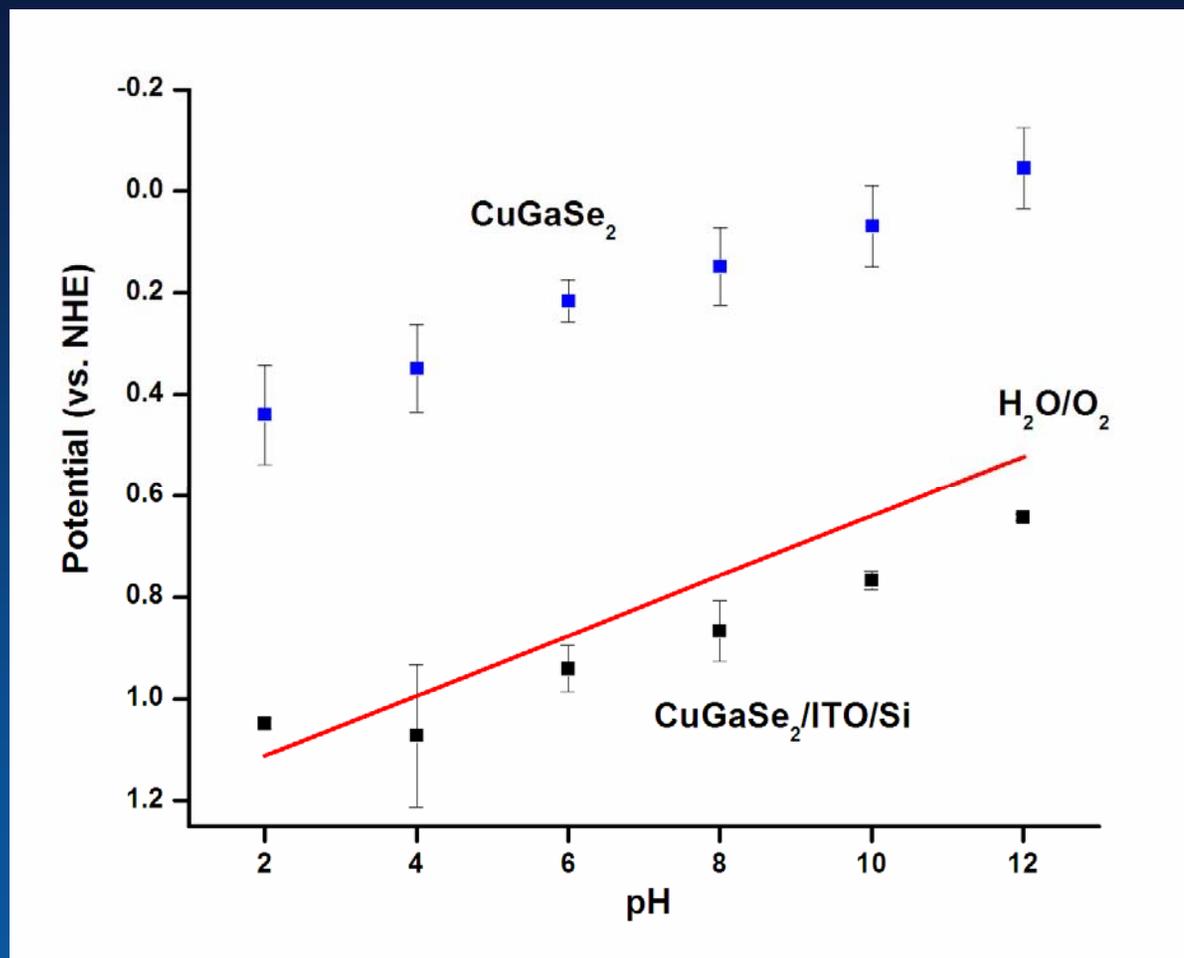


CGS: 1.3 $\mu m$   
ITO: 150nm



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# Results – Band Positions



Illuminated Open Circuit Potential Measurements  
High intensity DC W lamp illumination



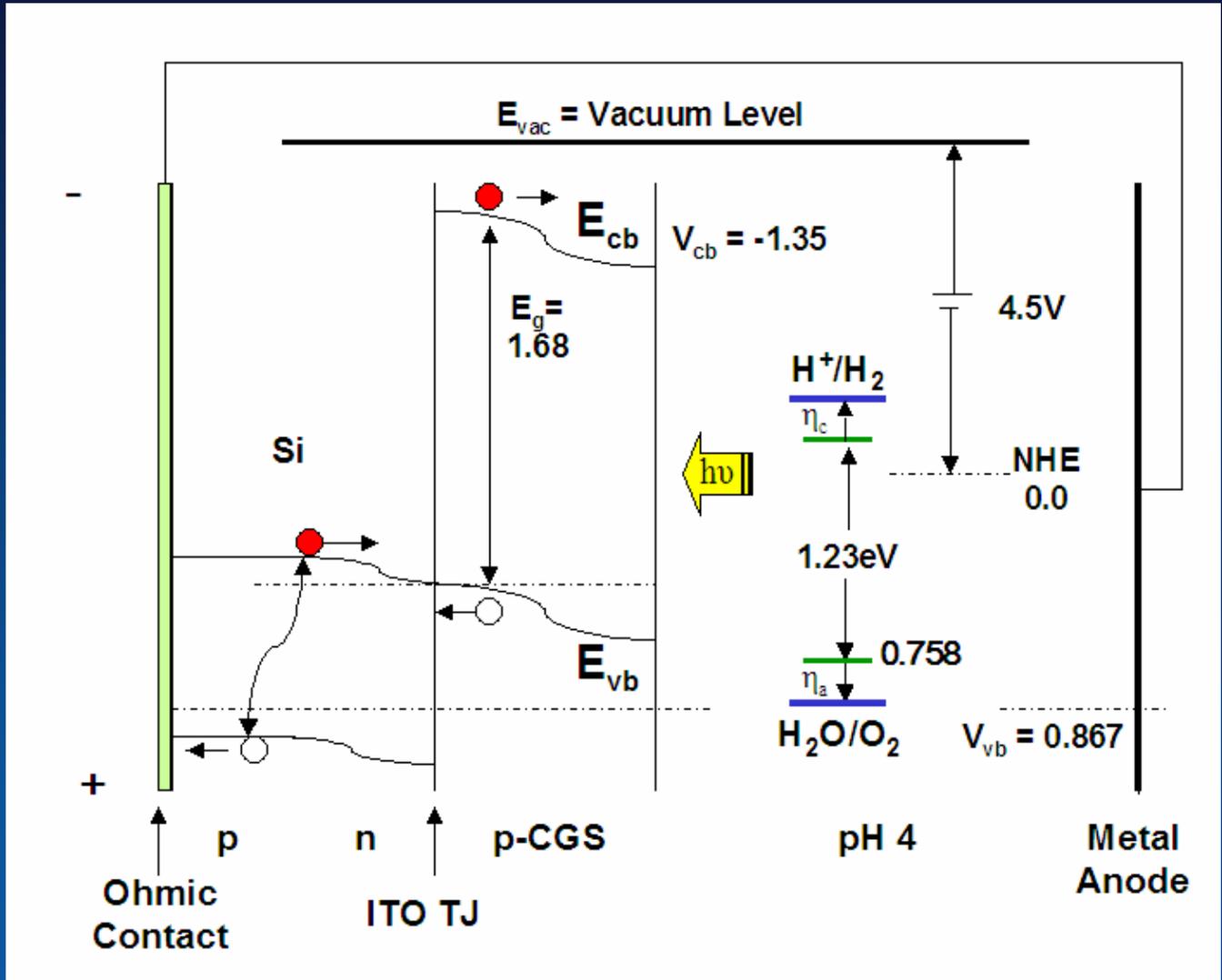
Jennifer E. Leisch

# Results – Band Energy Diagram

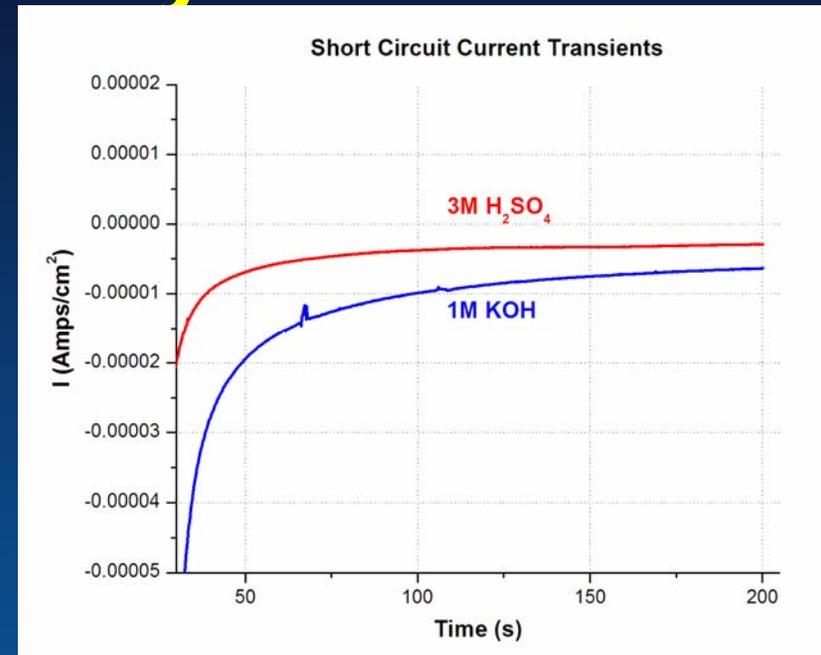
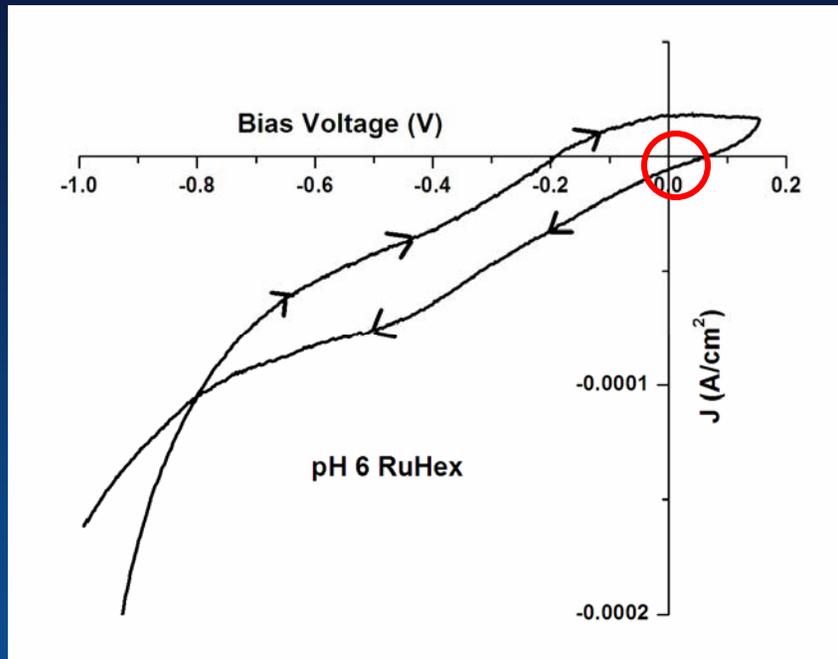
Energetics say:  
H<sub>2</sub>O splitting, but  
very low currents

Why?

- Poor ITO TJ
- Kinetics for H<sub>2</sub>
- Recombination
- Band shifting
- Corrosion



# Results – Water Splitting Efficiency



Possible band edge alteration on anodic scan. . .

$J_{sc}$  (Cathodic Scan)

pH 6 RuHex, 1sun

-5.7 $\mu$ A

Acid, ~ 20 Suns

-3.4 $\mu$ A

Base, ~ 20 Suns

-7 $\mu$ A

.01%



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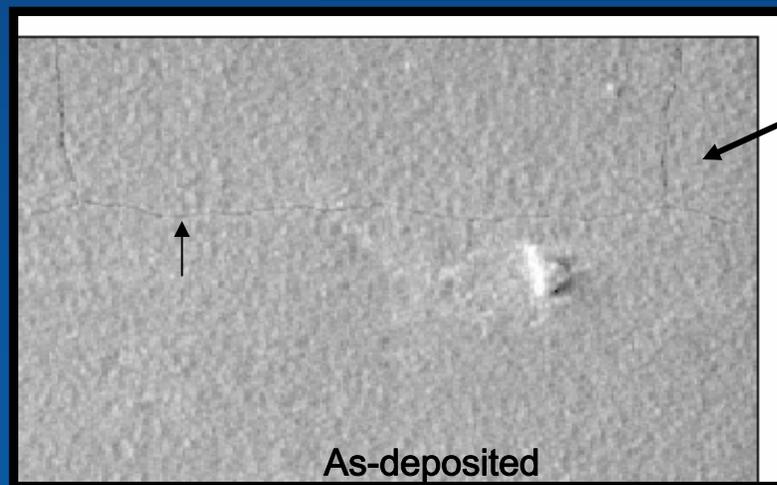
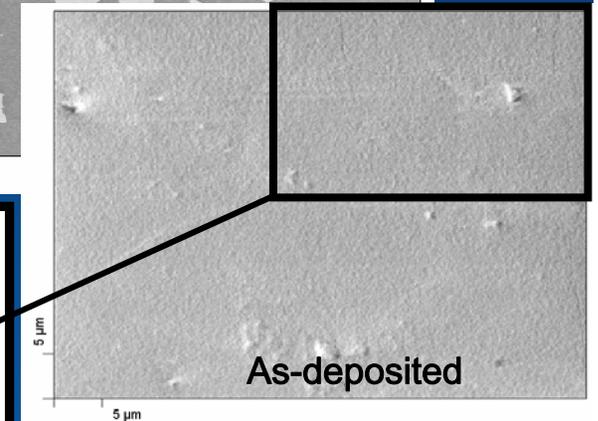
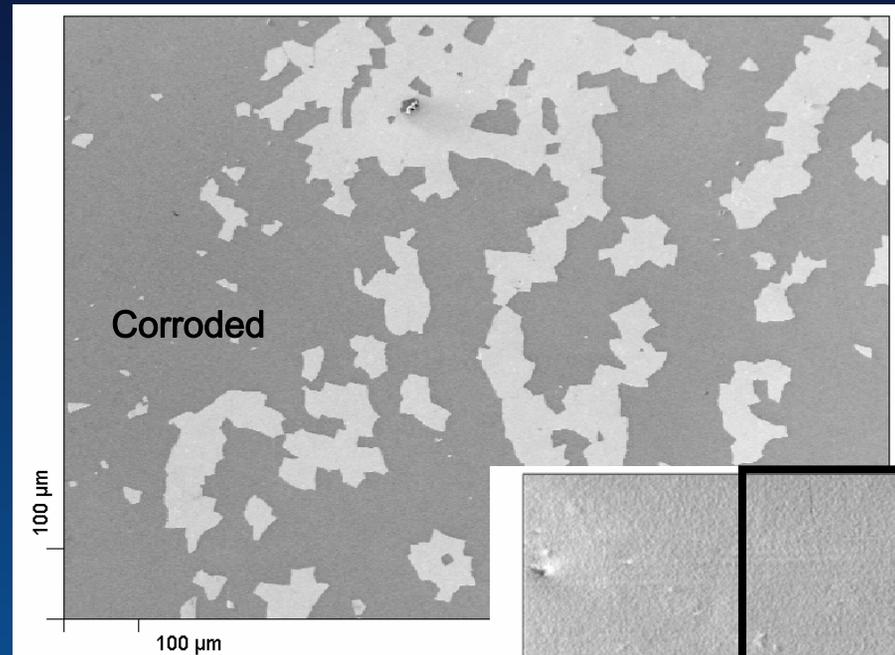
# Results – Stability

2mA/cm<sup>2</sup>, 3M H<sub>2</sub>SO<sub>4</sub>, 2hrs.  
100mW/cm<sup>2</sup> W Illumination

.03mL/min-cm<sup>2</sup> H<sub>2</sub> Evolution

The high temperature CGS deposition process damages the ITO layer.

Electrodeposition may be a better approach.

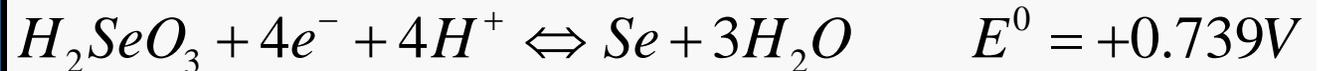
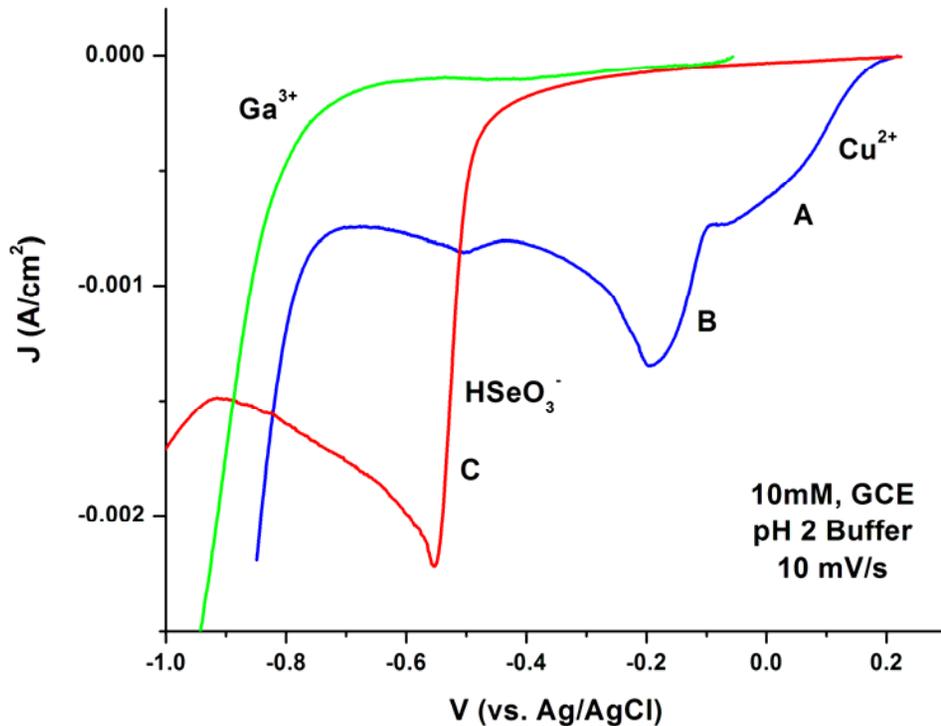


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## IV – Goal: Low-Temp CuGaSe<sub>2</sub> Deposition

# CuGaSe<sub>2</sub> Electrodeposition



Lincot, D., et al., *Chalcopyrite thin film solar cells by electrodeposition*. *Solar Energy*, 2004. **77**(6): p. 725-737.



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# Film Microstructure

Phases Present in XRD Patterns						
Cu:Ga:Se	-600mV	-700mV	-800mV	-900mV	-1000mV	-1100mV
1:10:0.5	Cu <sub>2-x</sub> Se					
1:10:1	CuSe					
1:10:1.5	CuSe, Cu <sub>3</sub> Se <sub>2</sub>	CuSe, Cu <sub>3</sub> Se <sub>2</sub>				
1:10:2	CuSe, Cu <sub>3</sub> Se <sub>2</sub>	CuSe				

## XRD

No Ga-containing  
phases observed



# Film Composition by ICP-MS

(inductively coupled plasma-mass spectrometry)

Cu:Ga:Se	-0.6V	-0.7V	-0.8V	-0.9V	-1.0V	-1.1V
<b>1:10:0.5</b>						
Cu (%)	41.86					
Ga (%)	32.68					
Se (%)	25.45					
<b>1:10:1</b>						
Cu (%)	33.18					
Ga (%)	30.71					
Se (%)	36.11					
<b>1:10:1.5</b>						
Cu (%)	39.03	32.06				
Ga (%)	1.76	21.73				
Se (%)	59.22	46.21				
<b>1:10:2</b>						
Cu (%)	37.14	33.32	33.69	31.85	35.47	27.00
Ga (%)	0.84	1.15	2.00	0.87	1.12	18.27
Se (%)	62.02	65.52	64.31	67.28	63.41	54.72

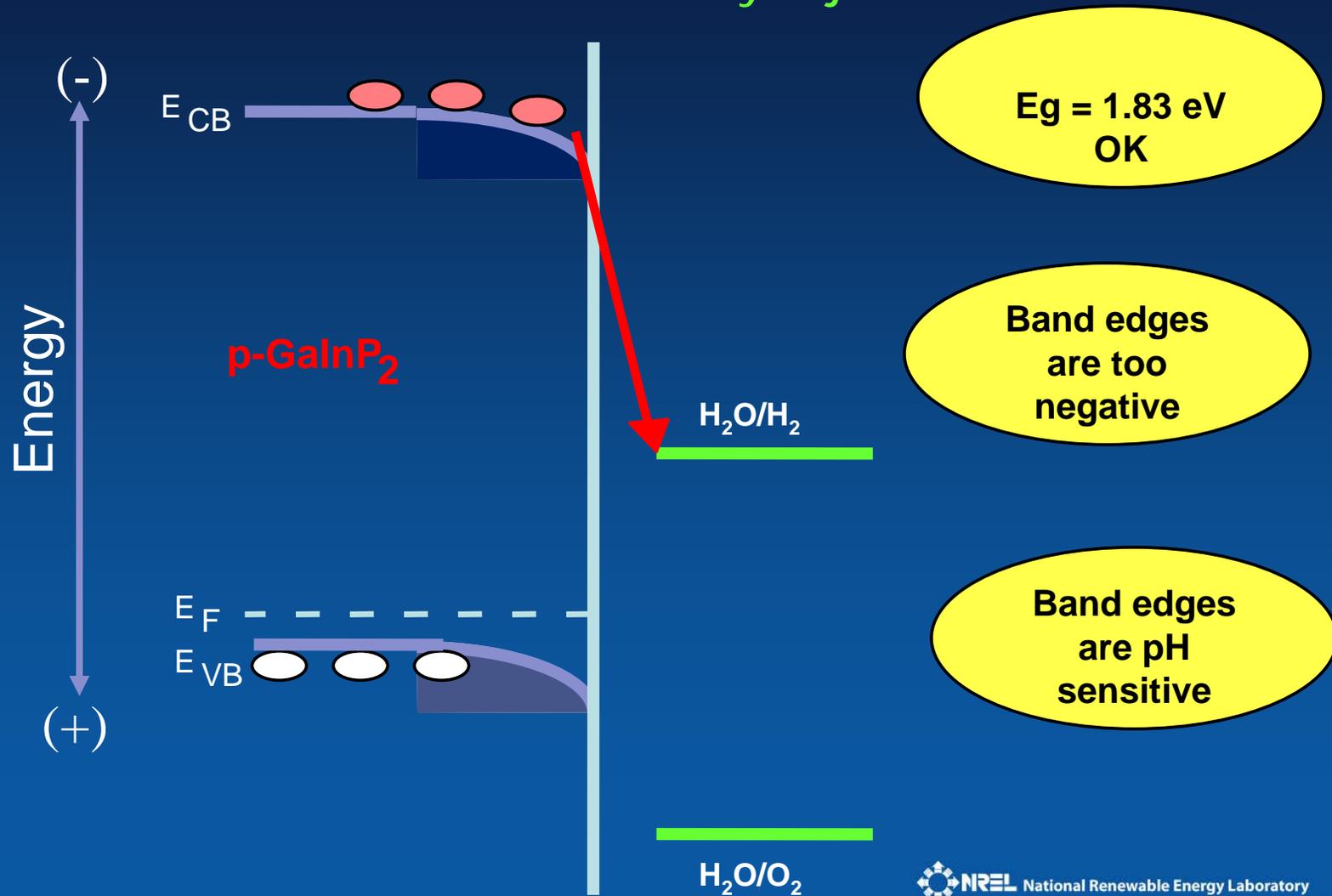
- Films close to the proper stoichiometry (1:1:2) were electrodeposited (ambient T and P)
- Gallium deposition can be obtained via codeposition mechanism
- Ga must be amorphous or of very small structure
- Excess Se inhibits Ga deposition
- Next step: Annealing

Dr. Jennifer E. Leisch



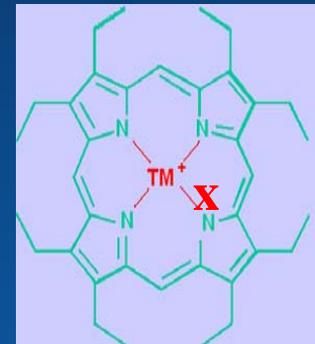
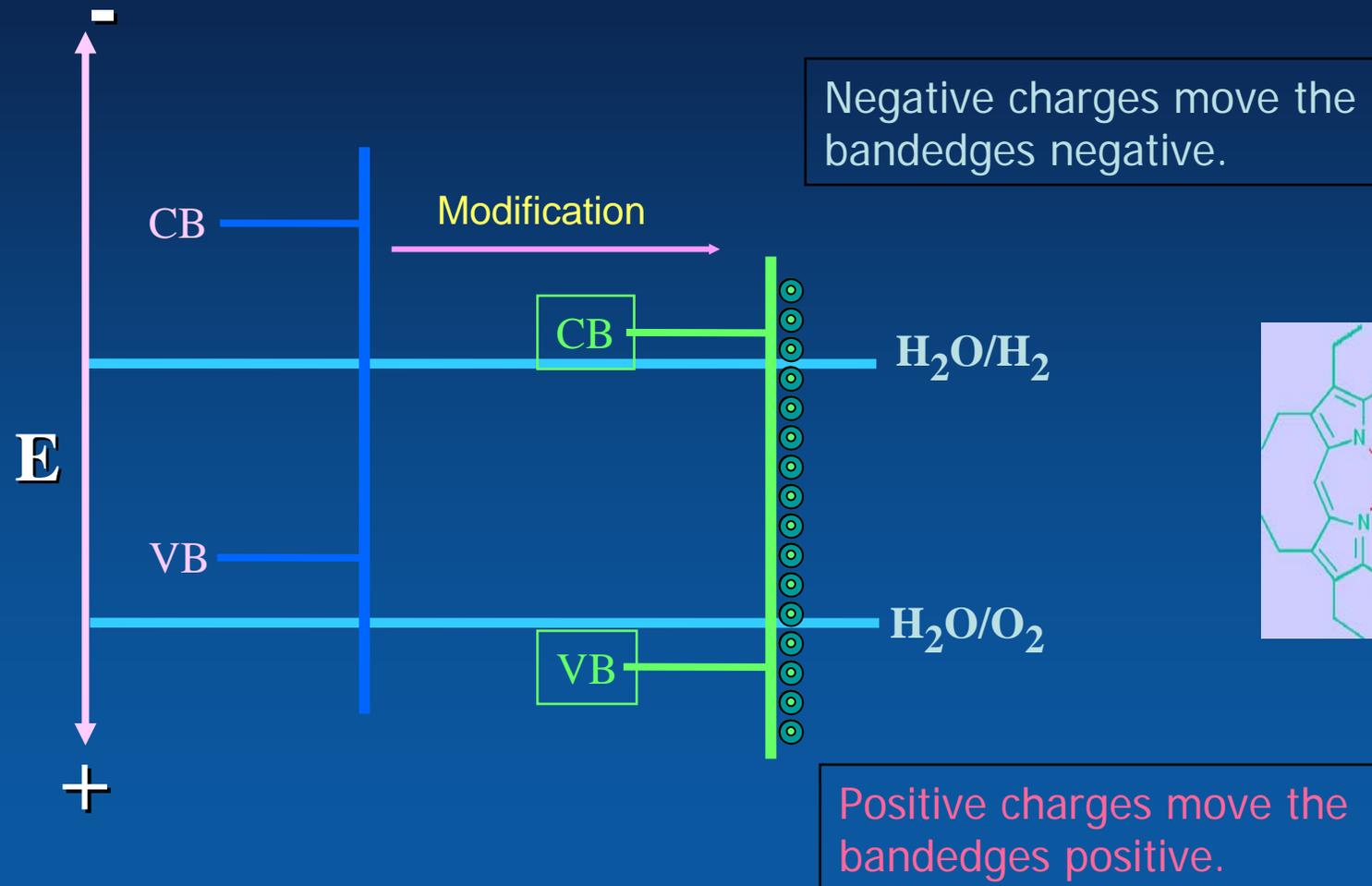
# Gallium Indium Phosphide/Electrolyte System

Used to gain a fundamental understanding of semiconductor/electrolyte junctions

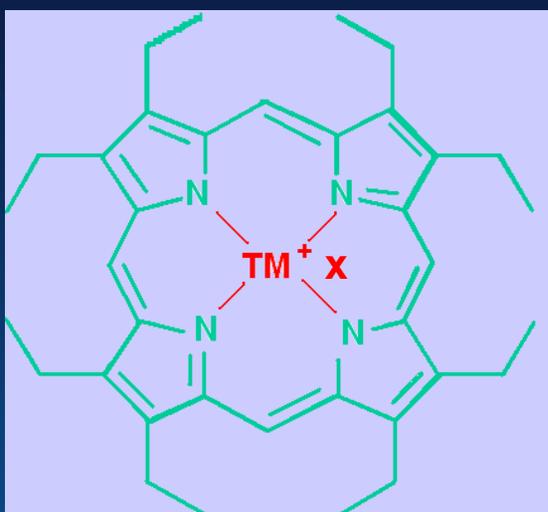


# Band Edge Engineering

The goal is to shift the band edges by surface modification to provide the proper energetic overlap.

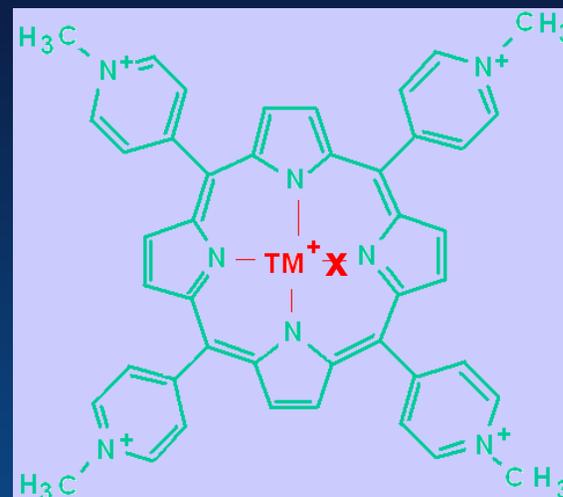


# Metallo-Porphyrins



Octaethyl Porphyrin

~OEP~



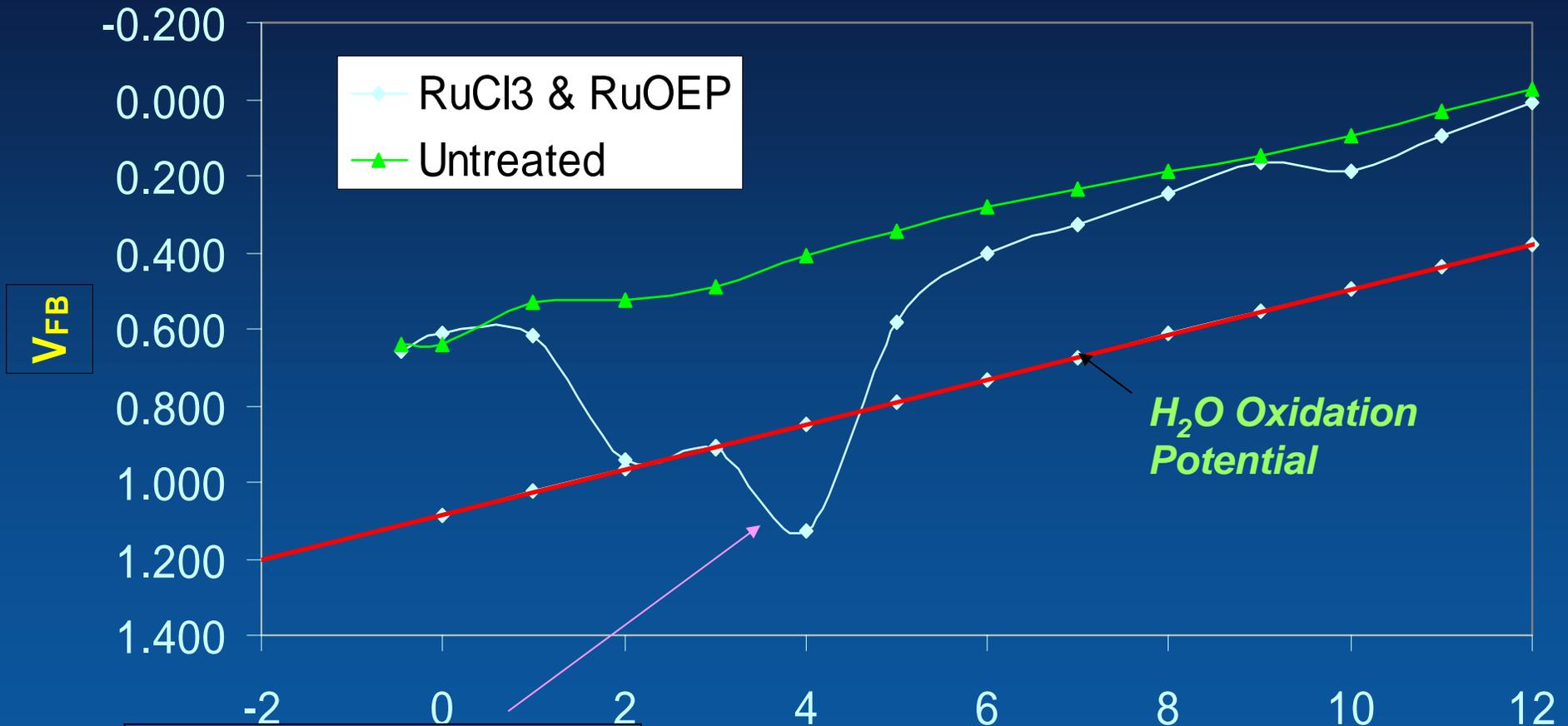
Tetra(N-Methyl-4-Pyridyl)porphyrin

~TMPyP(4)~

Insoluble porphyrin dissolved in methylene chloride and electrode coated by drop evaporation. Water soluble porphyrin applied by soaking the electrode in a solution of the porphyrin.

# Band Edge Engineering - GaInP<sub>2</sub>

$V_{FB}$  vs. pH for RuCl<sub>3</sub> + RuOEP Treated GaInP<sub>2</sub> Electrode



The band edges here should be able to split water....but no water splitting observed.

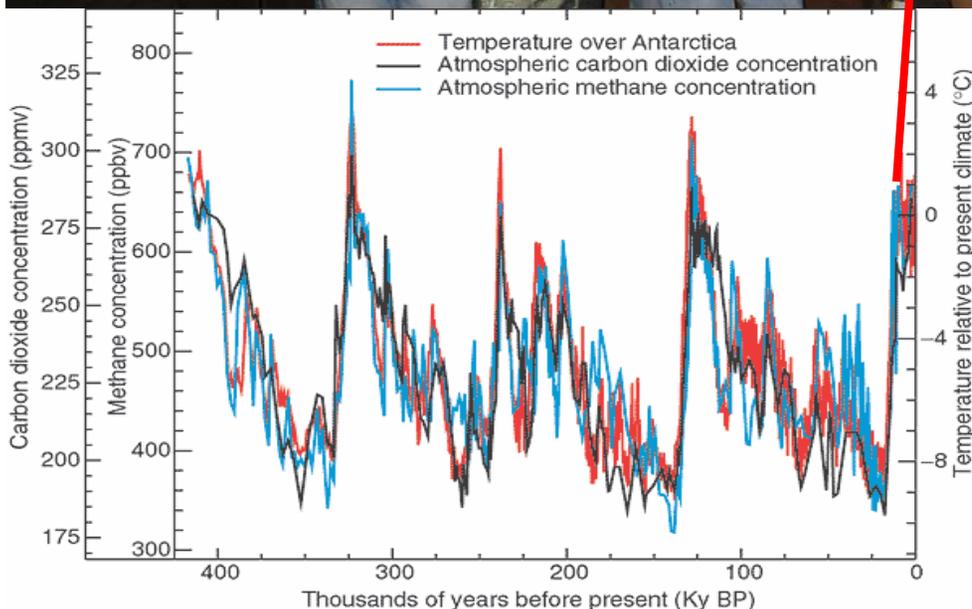
pH

S. Warren and J. Turner, *USDOE Journal of Undergraduate Research*, p 75 (2002)

# Photoelectrochemical Water Splitting



380 ppm



## Current Staff

Heli Wang

Todd Deutsch, Postdoc

Mark Reimann, Colorado School of Mines (PhD Student)

## Recent Past

Jennifer Leisch, Colorado School of Mines (PhD 2006 – now at Stanford)

Jeff Head, Colorado State University (SS- now at ASU)

Paul Vallett, University of Vermont (SS)

Scott Warren, Whitman College (SS - now at Cornell)

## Others

Vladimir Aroutiounian, University of Yerevan, Armenia (CRDF, ISTC)

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